

MEPTECReport

LED TECHNOLOGY
SPECIAL
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A Quarterly Publication of The Microelectronics Packaging & Test Engineering Council

Volume 17, Number 2

Eighth Annual MEPTEC

MEDICAL TECHNOLOGY CONFERENCE

*Global Momentum in the Medical Industry –
Convergence of Electronics, Biology and Health*

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2013 MEPTEC

SEMICONDUCTOR ROADMAPS SYMPOSIUM

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Located on the campus of Lorain County Community College in Elyria, Ohio, the Richard Desich SMART Center develops manufacturable packaging integration solutions for customers developing next generation microsystem products.

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MEMS firms need to leverage proven materials solutions that are market-ready and tested.

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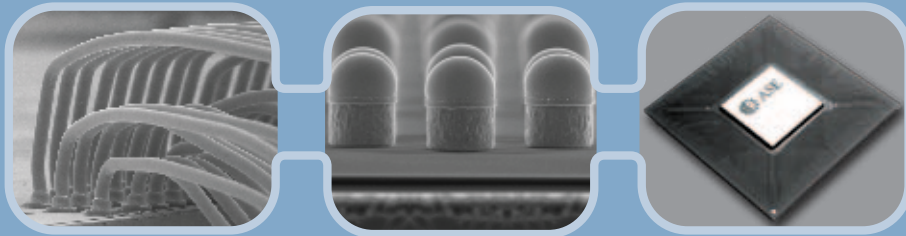
SnAg solder capped Cu pillar bumps emerge as alternative to C4 solder bumps.

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Medical MEMS Technology industry's interest in healthcare grows exponentially.



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MEPTEC Symposiums – Forwarding Visions and Predicting Industry Trends: Medical, MEMS and Packaging Roadmaps

*Nicholas Leonardi, Director of Business Development, Premier Semiconductor Services
MEPTEC Advisory Board Member
MEPTEC Medical Technology Conference, General Chairman
ASU / SBHSE, Advisory Board Member*

TECHNICAL SYMPOSIUMS ARE AN important part of the MEPTEC organizational structure with over 50 days of events to date and typically four events per year, covering a range of topics in electronics packaging and test. The direct extensive experience base of the MEPTEC Advisory Board Members and a diverse network of industry relationships in state-of-the-art technology has made reviews of Symposium Agendas very interesting. Review of the MEPTEC Web Site Symposium Proceedings (and CD Library) is literally a timeline for technologies and a significant indicator of their associated industry trends.

It was late in 1999, December 31st at 11:59 PM to be exact, with the organization having nearly 20 years of history with the MEPTEC Report publication and regional Luncheons, as the tech world held its breath and wine glasses, the computer clocks turned to 2000! Fortunately, within days, the advisory board focus was able to move from the “non-event” to an agenda for the first MEPTEC Symposium on Lead Free Solder Materials held in June. After the inaugural event in 2000, there were three Symposiums in 2001 with the big buzz in Opto-Electronics based on technology and investment capital. With the “Opto” industry event seen trending downward in 2002, events on Wafer Thinning, Wafer Level Packaging and Packaging Systems rounded out the four symposiums of the year, the new benchmark.

With events on RF Packaging and the cross-over between Component & Board Levels, 2003 was the year MEPTEC also presented events on MEMS Technology and Packaging Roadmaps (on a wide arrange of packaging topics), with both events continuing to be held on an annual basis. The con-

tinued interest and growth in both of these events is clearly an industry indicator. In particular, the technology and topics within the MEMS event continue to gain momentum based on product commercialization and expansion into other industries. Much in the way the Packaging Roadmaps event covers the range of packaging technologies, the MEMS technologies can be found in computing, communications, automotive, military, aerospace and medical industries. Receiving this issue of the MEPTEC Report will mean you are now able to access the CD's on the 11th Annual MEMS Symposium and plan participation and registration for upcoming Packaging Roadmaps event, as I am also planning on attending.

With the responsibility as General Chairman for the Thermal Technologies Symposium, which was initiated in 2005, it was very interesting to see this event transition to a co-location with IEEE SemiTherm and continuing on a positive trend based on the impact of heat on products. Transition of the Thermal event committee, in prior years, allowed for my complete focus on the Medical Symposium, initiated in September 2006 and held on the Arizona State University campus in Tempe, Arizona. Medical industry momentum and increasing support from the ASU School of Biological Health Systems Engineering (SBHSE), gave way to expansion in 2011 for a two-day symposium. This issue of the MEPTEC Report will be distributed to medical, electronic and biomedical industry experts attending, exhibiting and sponsoring the 8th Annual MEPTEC Medical Technology Conference. Committee members, speakers and sponsors are invited to the pre-symposium evening reception, which has become part of all the MEPTEC Symposium agendas. The

Medical event attendee reception, started in 2012, will be held again this year to showcase ASU SBHSE Student Projects, as they are involved in new product design and develop.

On behalf on the Advisory Board, your participation and feedback on Symposiums is appreciated, with these and other prior events including Solar, Known-Good-Die and 2.5D & 3D now in review. I look forward to meeting you at the Medical event to discuss current and future industry trends, as well as the “next trending technology”, positioning new MEPTEC events for key market visibility. ♦

NICK LEONARDI brings over twenty five years of electronics industry experience into his position as Director of Business Development for Premier Semiconductor Services. With current focus on new business development, previous key roles in engineering development, applications and sales management, with companies such as AMD, LSI Logic and GE. Primary areas of business development include the Counterfeit IC Detection Programs and the Lead Free Solder Conversion for BGA's and other package types. Industry affiliations and participation include; MEPTEC Advisory Board Member and Regional Co-Chairman, with support of other organizations including the FSA, SEMI, IEEE, IMAPS and SMTA. Nick received his B.S. Degree in Materials Engineering from Alfred University, New York.

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ON THE COVER

10 & 11 MEPTEC will present two events in September. The Eighth Annual MEPTEC "Medical Technology Conference" will be held on Tuesday & Wednesday September 17 & 18, 2013 at the Arizona State University Tempe Campus. The 2013 MEPTEC "Semiconductor Roadmaps Symposium" will be held the following week, on Tuesday, September 24, 2013, at the Biltmore Hotel in Santa Clara, California.

15 ANALYSIS – When it comes to the human body and the environment, there are dozens of sensors that can potentially be used to improve healthcare. There are acoustic sensors, chemical sensors, humidity or moisture sensors, navigation sensors, position sensors, optical sensors, pressure sensors, temperature sensors, proximity sensors, etc. Depending on the market, these sensors will be placed on different parts of the body, and different metrics will be used to determine the quality of movement and if a behavior change should or can be enacted.

BY MICHELL PRUNTY
SEMICO RESEARCH CORPORATION



17 PROFILE – The Richard Desich SMART Commercialization Center for Microsystems ("Desich SMART Center") is a microsystem packaging, assembly, and test development foundry. Located and part of Lorain County Community College in Elyria, Ohio, the Desich SMART Center develops manufacturable packaging integration solutions for customers developing next-generation microsystem products by leveraging world-class facilities and a highly experienced engineering team to accelerate product time to market.

DESICH SMART CENTER
MEMBER COMPANY PROFILE

21 SPECIAL – LED Technology, Packaging & Test Primer. Worldwide, there is a push to replace conventional energy inefficient light sources with solid state lighting. Considering incandescent bulbs alone, the EU, Switzerland, and Australia started to phase them out in 2009. Likewise, other nations are implementing new energy standards: Argentina, Russia, and Canada in 2014, and the US in 2014. The solid state lighting revolution based on LED technology holds incredible promise to reshape the lighting landscape.

BY SAI ANKIREDDI
SORAA INC.



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EV Group Rolls Out Next-Generation EVG120 Automated Resist Processing System for Micro- and Nano-Electronics Production



EV GROUP (EVG) HAS introduced the latest version of its EVG®120 automated resist processing system. Incorporating new features and improved productivity in an ultra-small footprint design, the EVG120 system supports coating and developing applications for a variety of markets, including microelectromechanical systems (MEMS), advanced packaging and compound semiconductors. The flexible

tool can be configured with combined spin and spray coating modules – a unique feature that maximizes productivity and optimizes cost of ownership.

The EVG120 automated resist processing system features a new robot with dual arms for fast wafer swapping and additional processing chambers, which result in enhanced throughput and overall productivity. To further optimize throughput and overall productivity, the new EVG120 runs the same EVG CIM Framework software as EVG's high-end XT Frame systems and offers full software integration with SECS/GEM standards. Two customizable wet processing

bowls are complemented by 10 stacked modules for vapor prime, soft and hard bake, and chill processes. Like its predecessor, the EVG120 system can accommodate wafers up to 200 mm in diameter.

Further improved serviceability and low CoO make the EVG120 system a versatile, high-quality production tool for an entry-level budget. The EVG120 system is ideally suited for a wide variety of markets and applications, including: high-topography coating and spray coating for MEMS; thick-film resists and bumping for advanced packaging; and passivation, dielectrics and thick-film processing.

More information is available at www.EVGroup.com. ♦

Altera to Deliver Breakthrough Power Solutions for FPGAs with Acquisition of Power Technology Innovator Enpirion

Industry's Most Integrated Power Solutions Reduce Power, Provide Smallest Form Factor and Simplify System Design

ALTERA CORPORATION has announced it has signed a definitive merger agreement to acquire Enpirion, Inc., the industry's leading provider of high-efficiency, integrated power conversion products known as PowerSoCs (power system-on-chip). The combination of Altera's FPGAs with Enpirion's PowerSoCs will offer customers higher performance, lower system power, higher reliability, smaller footprint and faster time-to-market.

"Power is increasingly a strategic choice for product differentiation in communications, computing and enterprise, and industrial applications," said John Daane, president, CEO and chairman of Altera. "By adding a power group to Altera, we will bring even more value to system-level designs. Altera's FPGA roadmap will be enhanced



significantly with the addition of Enpirion's power technologies."

Enpirion's key enabling power technologies – high-frequency switching, magnetics and packaging – are engineered into complete power system-on-chip products. Enpirion's portfolio of DC-DC converter PowerSoCs with integrated inductors enable the industry's smallest solution footprints and are recognized for their high efficiency, low noise, exceptional thermal performance, high reliability and ease-of-

use. Unlike discrete power products, Enpirion's turnkey solutions give designers complete power systems that are fully simulated, characterized, validated and production qualified.

Find out more about Altera FPGAs, SoCs, CPLDs, and ASICs at Altera.com.

Enpirion, Inc. is a privately-held, analog semiconductor company with expertise in highly integrated power conversion solutions. Enpirion is headquartered in Hampton, NJ. Visit enpirion.com for more information. ♦

▶ AMKOR APPOINTS STEVE KELLEY PRESIDENT AND CEO

Amkor Technology has announced that Stephen D. Kelley has been appointed to serve as President and Chief Executive Officer and as a director of the Company. Mr. Kelley succeeds Ken Joyce, who previously announced his intention to retire. Mr. Kelley's appointment follows a comprehensive, six month search process conducted by the Board of Directors with the professional assistance of a global executive recruiting firm.

www.amkor.com

▶ LSI RANKED NO. 1

LSI Corporation has announced it achieved the No. 1 position in worldwide solid state drive (SSD) controller revenues for 2012, according to figures recently released by Forward Insights, a leading IC market research firm. According to the report, LSI grew its revenue share in 2012 to 38 percent, nearly twice the share of the closest competitor.

www.lsi.com

▶ DONATED FINE-TECH DIE BONDER INSTALLED AT PENN STATE UNIVERSITY

Finetech, as part of the company's 20th anniversary last year, held a donation drawing for a \$100,000 high-accuracy bonding system that was open to universities and colleges. Penn State was the randomly selected winner out of nearly 400 entries. A FINEPLACER® pico bonder has now been installed at



the MEMS Nanoscale and Devices Group at Penn State. This was Finetech's way of giving back to the university R&D segment of its business.

mnd.ee.psu.edu/index.asp


► STATS CHIPPAC SINGAPORE GRAND OPENING

STATS ChipPAC Ltd. has celebrated the grand opening of its new building in Singapore with more than 150 distinguished guests, including Singapore Deputy Prime Minister and Coordinating Minister for National Security & Minister for Home Affairs, Mr. Teo Chee Hean. STATS ChipPAC has invested approximately US\$1.7 billion in Singapore to date to expand its technology offerings and manufacturing capacity. Singapore has become the Company's global hub for advanced wafer level technology R&D and wafer level packaging centre of excellence for advanced mobile devices.

www.statschippac.com

► AMD UNLEASHES FIRST-EVER 5 GHZ PROCESSOR

AMD has unveiled its most powerful member of the legendary AMD FX family of CPUs, the world's first commercially available 5 GHz CPU processor, the AMD FX-9590. These 8-core CPUs deliver new levels of gaming and multimedia performance for desktop enthusiasts. AMD FX-9000 Series CPUs will be available initially in PCs through system integrators.

The new 5 GHz FX-9590 and 4.7 GHz FX-9370 feature the "Piledriver" 

InvenSense® Unveils World's Lowest Profile 6-Axis MotionTracking Device

MPU-6521 Integrated Gyroscope and Accelerometer in a 3 x 3 x 0.8mm Package

INVENSENSE, INC., THE leading provider of MotionTracking™ devices, has announced the MPU-6521 MEMS SoC, which is the world's smallest, lowest profile, and lowest power 6-axis solution. The slim profile MPU-6521 is targeted for the next-generation of smartphones, tablets, gaming devices, motion-based remote controls, and wearable sensors.

At 6.1mW, the MPU-6521 consumes 60% less power than competing solutions. To enable the precision required for pedestrian navigation and

wearable sensor applications, the MPU-6521's integrated gyroscope achieves low noise performance of 0.01 dps/vHz. The MPU-6521 MEMS SoC includes the patented Digital Motion Processor™ (DMP) with integrated MotionFusion™, run-time calibration, and system-level power optimization features.

"InvenSense is enabling the thinnest consumer electronics on the market. By leveraging our patented technology platform, InvenSense enables lower profile designs while at the same time delivering the performance that

competitors can not achieve with their legacy MEMS manufacturing processes," said Ali Foughi, Vice President of Marketing and Business Development at InvenSense. "With the MPU-6521, we are setting a new industry standard and extending our market leadership."

The MPU-6521 will be sampled to select customers in Q2'13.

For additional information and data sheets, please visit www.invensense.com or contact InvenSense Sales at sales@invensesense.com. ♦

ASE's Profit Beats Expectations

ADVANCED SEMICONDUCTOR ENGINEERING INC. (ASE) has reported a better-than-expected first-quarter net profit as customers' inventory digestion ended earlier than expected.

While net profit fell 49 percent to NT\$2.23 billion (US\$75.07 million) last quarter, from NT\$4.37 billion in the fourth quarter last year, it was up 8.79 percent from NT\$2.06 billion in the same period last year. The figure is also better than the NT\$1.78 billion estimated by Credit Suisse analyst Randy Abrams.

"Revenue only dropped 10 percent sequentially in the first quarter, which is better than our estimate of a decline of 10 to 13 percent. Customers completed their inventory digestion in January or February," ASE chief financial official Joseph Tung told investors.

For this quarter, ASE expects its packaging and testing business to grow between 11 percent and 14 percent from last quarter, Tung said.

Growth in the communications segment, primarily smartphone clients, would outpace that of computing and consumer sectors, Tung said.

ASE generated more than half of its revenue of NT\$31.32 billion from the communications segment last quarter.

ASE's guidance generated a lot of discussion at the investor conference as the growth figure was higher than the estimates of most analysts, including Abrams, after Qualcomm Inc., one of ASE's major clients, projected a 6 percent

sequential decline in shipments this quarter.

Abrams expected ASE's revenue to grow about 12 percent sequentially in the current quarter. He has an "outperform" rating on ASE, with a price target of NT\$27.20.

"Our forecast is based on what we've heard from our customers," Tung said.

He attributed the bigger-than-expected growth to customer diversification and market share gains.

Gross margin for chip packaging and testing services, which dipped to 19.9 percent last quarter, is expected to recover and surpass the 23.2 percent recorded in the fourth quarter last year, boosted by a favorable foreign exchange rate, a potential decline in gold prices and lower depreciation expense, Tung said.

The company expects the price of gold to slide about 11 percent to US\$1,520 per ounce, from US\$1,673 per ounce last quarter. Every US\$50 decline in the gold price would boost ASE's gross margin by as much as 0.15 percentage points, Tung said.

Factory utilization for its advanced packaging service, mostly for smartphone chips, would rise to 85 percent this quarter from 79 percent last quarter, while the utilization rate for its testing equipment would increase to above 80 percent from 75 percent, he added.

ASE has retained its projected capital spending for this year at between US\$600 million and US\$700 million. ♦

Mühlbauer and Novacentrix Enter Long-Term Collaboration for Developing a Flexible and Cost Effective RFID Antenna Printing Technology

Mühlbauer and NovaCentrix are pleased to announce the establishment of a formal collaboration to bring to market advanced new RFID antenna manufacturing technology. Under the agreement, Mühlbauer will develop, produce and market scalable antenna production systems "APS" for RFID inlay/label manufacturers incorporating NovaCentrix' state-of-the-art PulseForge photonic curing tools and optimized for use of NovaCentrix' low-cost, high-performance Metalon ICI copper oxide reduction inks.

With this step Mühlbauer is finally completing its long-term strategy to provide a complete turn-key solution for realizing the most flexible, fully integrated and cost efficient RFID factory including antenna production, inlay assembly, label converting and personalization.

"We are committed to providing our customers the most suitable technologies for all production steps to be successful in RFID inlay and label manufacturing," said Thomas Betz, Member of the Management Board for Mühlbauer. "Based on our careful evaluation of the PulseForge tools and Metalon ICI inks, we believe partnering with the NovaCentrix team is in the long-term best interests of Mühlbauer and our customers for realizing the most efficient RFID antenna manufacturing – directly before attaching the chip."

The first version of the reel to reel antenna manufacturing line, "APS 20000", will be designed to provide a capacity of 100 million antennas per year. Bigger versions will be available upon market request. The system consists of modules for printing, drying,

photonic curing, and quality control. Other processes can be integrated on request. The goal of this highly flexible and scalable concept is to further increase the competitive advantages of the RFID inlay and label manufacturers by enabling them to produce their antennas in house with very short reaction times and to achieve further cost reduction by a significantly improved cost of ownership, especially for antennas on paper substrates.

The PulseForge® family of tools uses the patented photonic curing process to heat functional inks and thin films in milliseconds without heating underlying or adjacent substrates. The tools are used to dry, sinter, or anneal thin-film materials

on substrate materials such as polymers and paper. Unlike traditional oven technologies, the transient nature of the process heats thin films to a high temperature on low-temperature substrates without causing damage. The low-cost Metalon ICI series of inks are formulated with copper-oxide nanoparticles along with a reduction agent, in water. After the ink is printed, a PulseForge tool is used to drive a reduction reaction thereby converting the copper oxide into a thin film of highly conductive copper. Importantly, this process is performed in ambient air on low temperature substrates at speeds exceeding 30 meters/minute. For more information visit www.muehlbauer.de and www.novacentrix.com. ♦

architecture, are unlocked for easy overclocking and pave the way for enthusiasts to enjoy higher CPU speeds and related performance gains.

The new AMD FX CPUs will be available from system integrators globally beginning this summer.

www.amd.com

► ULTRATAPE MOVES TO A NEW FACILITY

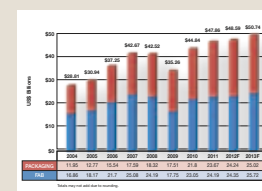
UltraTape Industries, a division of Delphon, and the premier supplier of Cleanroom tapes and labels has moved to its new 22,000 square foot facility. Located in Wilsonville Oregon, this larger state-of-the-art facility increases UltraTape's capacity and expands the company's Class 100 cleanroom manufacturing capabilities.

www.cleanroomtape.com

► CORRECTION

The Spring 2013 issue of the MEPTEC Report contained an error in the *Analysis* article by Jim Walker and Mark Stromberg of Gartner. An incorrect total appears in Table 1 for the year 2010 Revenue. The total should have been 23,592, not 25,593.

The *Analysis* article in the Winter 2012 issue of the MEPTEC Report contained a production error in Figure 1. The values of the red and blue bars in the chart were shown in reverse order. The correct image is shown below. ♦



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2013 IC Packaging and Economic Outlook

AFTER 2009 BEING THE WORST depression since the Great Depression in the 1930s through the mid-1940s, the integrated circuit (IC) industry had a boom in the second half of 2010. 2011 began well on the heels of this boom, but a slowdown in the market in the second half of that year caused a negative growth rate, a pattern that repeated in 2012. The inventory corrections in these two years did not alter the fact that both 2011 and 2012 still had near-record-breaking unit and revenue figures. And of course the growth rates of 2010, with revenue growing 40 percent over 2009 and units 35.5 percent, were not sustainable.

Sales of tablets, smart phones, and automobiles are going well, and they are carrying the rest of the economy forward into recovery. Apple Computer had one blockbuster product after another, with the iPod, iPad, and iPhone. Apple, once the most valuable company in the world, is now number two behind Samsung. Producing portable electronic gadgets that connect people electronically with the world around them is clearly a good business model. Even in the depths of the recession of 2009, electronic gadgets that connected people via the Internet and sold for under \$400 did well.

IC Revenue

Figure 1 illustrates IC revenue growth for the entire IC chip market. Revenue growth will be a steady increase through 2017, a similar trend to unit growth, and will have a 5.2 percent CAGR. The packaging revenue percent of IC revenue is

shown at the bottom of this figure. The packaging revenue percent of IC revenue is displayed as well. Though it varies greatly by device type, overall packaging consumes slightly more than 15 percent of the total chip revenue and will rise to slightly more than 16 percent.

For more in depth forecasts on IC packaging, please refer to *New Venture Research's newly published report, The Worldwide IC Packaging Market, 2013 Edition*. This report presents forecasts for each semiconductor product type, and segments these products by package family and I/O count range. Packaging revenue figures are displayed for each segment, based on prices charged in the outsourced assembly and test (OSAT) market. The package families are then rolled up by I/O count and semiconductor product. In doing so, the report generates the total value of the IC packaging industry.

Next, the report presents NVR's continuing, extensive coverage of the OSAT market. OSATs will continue to assume a larger share of the world's IC packaging business. The report breaks the OSAT market down by package families and major product categories providing units and revenue for each category. To further assess this group of companies, the report profiles the activities of the world's largest OSAT companies and the packages they offer.

For more information on how to obtain this report, please contact Karen Williams at kwilliams@newventureresearch.com, Tel: (408) 244-1100, or Sandra Winkler at slwinkler@newventureresearch.com, (650) 299-9365. ♦

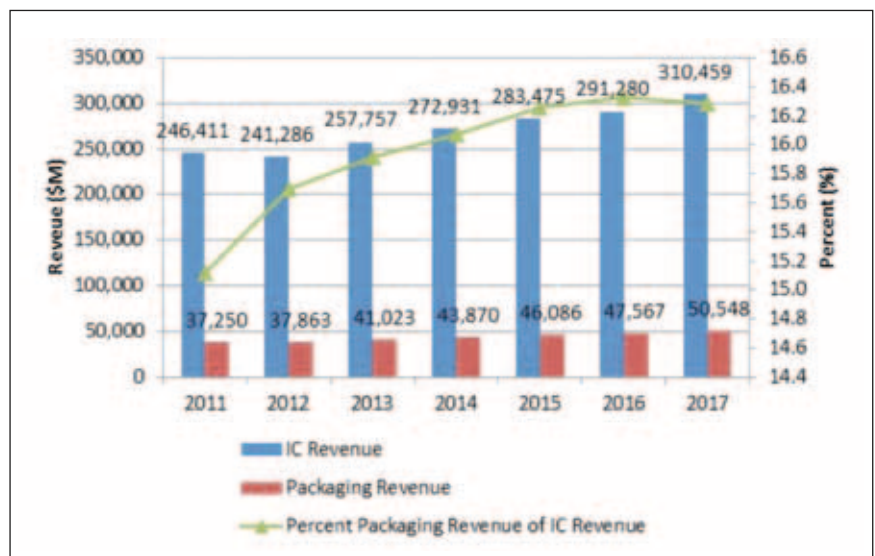


Figure 1. IC and Packaging Revenue Forecast and Percent of Packaging of Total, 2011-2017.

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[Packaging]

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Advanced packaging is in the early stages of an exciting era of growth and innovation. Demand for equipment and related tools in the 3D-IC and wafer-level packaging area is forecasted to grow from approximately \$370 million in 2010 to over \$2.5 billion by 2016 (*Yole Développement*).

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2013 MEPTEC MEDICAL TECHNOLOGY CONFERENCE

*Global Momentum in the Medical Industry –
Convergence of Electronics, Biology and Health*

Tuesday & Wednesday, September 17 & 18, 2013
Arizona State University, Tempe Campus

MANY FACTORS HAVE contributed to global momentum in the medical electronics industry, with the convergence of electronics technology and biological health sciences playing a major role. Growth in medical electronic applications (yes, there is an App for that!) will parallel Cell Phone and Tablet PC markets, with increases in computing power as well as optical resolution and touch sensor technologies. Current focus for mobile, implantable and large medical systems is on improved personal health, with preventative applications and advanced early diagnostics. Various integrated circuit (IC) technologies, now complemented by MEMS bio-sensor technologies, allowed for significant development in areas such as prosthetics, combining “artificial limbs” with “artificial intelligence”, sensing and reacting to very small electrical impulses from the brain, through direct body contact.

This conference will address the many industry challenges and opportunities including safety, reliability, miniaturization, manufacturing and



OLD MAIN on the ASU Tempe Campus, constructed before Arizona achieved statehood, will host the 8th Annual MEPTEC Medical Electronics Conference.

A combination of technical, market and health topics will be presented through presentations and panel discussions. Topics to-date include:

- Safety and reliability of medical devices
- MEMS and Mobile Health Care market overview
- Bonding techniques of new wire alloys for medical electronics
- Wafer Level Packaging and TSV for biomedical applications
- MEMS & Sensors for Medical Applications
- Security and psychological issues in medical devices
- Miniaturized electronic packaging for wearable health monitors
- Wireless communication/solid state batteries in miniature implantable medical devices
- Designing more reliable medical products
- “Fantastic Voyage” meets medical device design

materials as well as government regulations and political healthcare initiatives. The human body is a convergence of various biological phenomena and sophisticated electrical net-

works controlled by the brain, with the health sciences and medical electronics technologies converging to meet strong global demand. ♦

KEYNOTES



Sam Bierstock, M.D.

Day One Keynote

MEMS Technology and the Healthcare Industry: The Convergence of Timelines and the Perfect Storm

Sam Bierstock, M.D., BSEE Physician, Electrical Engineer, Medical Informaticist, Founder of Champions in Healthcare

Dr. Bierstock is a nationally recognized authority on healthcare and healthcare information technology. He is the Recipient of the George Washington Honor Medal, Freedoms Foundation for his work on behalf of our nation's veterans. ♦



Karthik Vasanth, Ph.D.

Day Two Keynote

Creating Solutions for Health Through Technology Innovation

Karthik Vasanth, Ph.D. General Manager, Medical and High Reliability Business Unit Texas Instruments

Karthik Vasanth received his Ph.D degree in Electrical Engineering from Princeton University in 1995. He joined the Silicon Technology Development group at Texas Instruments in 1995. In 2010 he became the General Manager of the Medical and High Reliability Business Unit at TI. ♦

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*A Collaborative Update from
Standards Bodies, Industry Groups, and Large OEMs*

September 24, 2013 • Biltmore Hotel, Santa Clara, CA

In the spirit of collaboration, this event will consist entirely of panel discussions, rather than traditional presentations. This will allow for more interaction among the speakers and attendees, so that the synergies, gaps, and differences of opinion can be explored more thoroughly. A day full of panel discussions will also allow representatives of more companies, including device manufacturers and large OEMs, and industry and standards organizations, to present their views. Join us for this first-of-a-kind collaborative event!

Over the years, MEPTEC's popular Roadmaps events have been attended by high level managers, CEOs, and CTOs, looking for validation and insight into technology and business directions for their companies, for their suppliers and, in some cases even their customers. At past events they, and their competitors who were presenting their own roadmaps, were looking for strategic help and

metrics of progress.

During its long and successful existence, MEPTEC has recognized the need for one essential ingredient above all others in achieving success with any semiconductor industry roadmaps: collaboration.

First, collaboration among trade associations, standards groups, OEMs, providers of analytic and design software, sub-contract service providers, and suppliers throughout the supply chain is increasingly critical to success. Second, as distinctions among semiconductor processing, packaging and assembly technologies, and design/testing protocols are disappearing manufacturers have greater need for collaboration.

The MEPTEC Roadmap event will bring together standards groups, industry groups and consortia, industry experts, device manufacturers, and representatives of the large OEMs to update their roadmaps and development activities, which may include 2.5D/3D as well as other driving factors pertinent to their business segments. Join us for this first-of-a-kind collaborative event! ♦



The Biltmore Hotel is conveniently located at 2151 Laurelwood Road in Santa Clara, CA in close proximity to the San Jose Airport.

Symposium Topics will include:

- **Market Drivers** – the current and future products that continue to drive semiconductor packaging down the road of “smaller, faster, and cheaper” – logic, memory, power, other (including MEMs and sensors)
- **Packaging needs** expressed by the major device manufacturers (ODMs), the end customers (OEMs), and the assembly and test suppliers (OSATs and EMS) Non-mechanical performance needs including interconnections, transmission speeds, switching protocols, new reliability requirements.
- **Non-mechanical performance needs** including interconnections, transmission speeds, switching protocols, new reliability requirements.
- **Status of efforts** of various Consortia, Standards groups and trade organizations to support their members and to help establish infrastructure.

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INDUSTRY INSIGHTS

By Ron Jones



That Other Dimension

► THE EARLY BEGINNINGS OF the semiconductor industry were in three dimensions. Transistors were manufactured typically from germanium or silicon as 3 dimensional devices in various configurations. They involved tiny pieces of semiconducting material handled individually, not manufactured in wafer form. Over time, wafer processing was introduced, but transistor structures were built above the surface which limited mass production. The jump to a two-dimensional world occurred when Dr. Jean Hoerni, one of the Fairchild Traitorous Eight, developed the planar Process in 1959. The transistor structures were built into the surface of a wafer, thus enabling mass production.

The ensuing 50 years is pretty much a two-dimensional story for chips. The move from transistors to monolithic integrated circuits in the 60's drove the need to interconnect various transistors and resistors on the surface of the IC chip. This metal was placed on the surface of the wafer instead of built into the surface but all processing was in 2 dimensions. As the complexity of integrated circuits moved from a few transistors on a chip to 10's of billions today, there was a need for many more interconnect layers. As they were above the surface, the metal on each layer created a bump on the surface. As multiple layers were applied, the surface would become increasingly bumpy causing problems with accurate patterning. To avoid this problem, we introduced chemical-mechanical polishing (CMP).

After each metal layer is patterned, a thin non-conductive material is applied to the surface of the wafer. The CMP process grinds down the non-conductive layer until the metal is exposed, thus providing a flat surface to the wafer. The move from aluminum metallization to copper facilitates this as copper is a much harder material and easier to detect when reached. Though the metal layers are applied in a vertical direction, CMP

utilizes two-dimensional processing.

After more than 50 years of building transistors into the surface of the wafer, enter the FinFET in various configurations. These multigate transistors are built on the surface of a wafer. They offer advantages in reduced leakage current and power dissipation. As we move forward, there will likely be other structures, involving things such as nanotubes that will be built on top of the wafer. Though these are built on the surface, they still generally involve processing in two dimensions with wafers and photo-masks.

Many challenges face the fab folks beyond just building the structures as they must characterize the devices and develop in line measurement tools to control the processes. In many cases, the metrology tools and characterization tools don't exist today to control this 3D world.

As we move to the assembly area, things are beginning to get much more 3 dimensional in processing. Most of what I'm talking about is stacking die on top of each other. 3D involves stacking die directly on top of die, through there are a number of different configurations. 2.5D utilizes an interposer layer between that aids in mating the two die.

Compared to packages many years ago that were standard with specs that lasted for years, many of the advanced schemes today utilize a number of different assembly technologies and IP to construct a package this is custom for a particular end product. We utilize TSV's (through silicon vias), myriad bumping technologies, substrates of varying composition, layers and form factors to cobble together a solution.

One of the issues this "custom package" creates is operating and reliability characterization of a complex interconnected system. Fortunately, we have many well characterized building blocks that minimize the risk. We have good characterization tools for electrical and power modeling in two dimensions, but limited tools for characterization in 3 dimensions. This will need to improve over time.

As you begin to stack more and more die, the probability of a weak link or incompatibility issue rises. This would be less critical if rework was easy, but in many cases, it is impossible to rework a stack to replace in interposer or chip in the stack. One defect can mean scrap all.

Die stacking is an approach that still

has physical limitations. Just as we went to TSOP's and then chip scale packages to fit in thin form factor products, so we have height limitations on many of today's smart phones, tablets, etc. Though you may be able to reliably and cost effectively stack 8 memory chips on top of each other, the product may not be able to accept this height.

There are many companies and industry segments (foundries, OSAT's, 3rd party processors, IP licensors, etc.) that are active in the space, all trying to carve out a significant place. As I've said before, there is not going to be one big winner, either company or segment.

One thing you can be sure of is that we will take the challenges in stride and find new, reliable, cost effective solutions that enable increasingly more complex end products. ♦

RON JONES is CEO and Founder of N-Able Group International. Visit www.n-ablegroup.com or email Ron at ron.jones@n-ablegroup.com for more information.



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COUPLING & CROSSTALK

By Ira Feldman



Electronic coupling is the transfer of energy from one circuit or medium to another. Sometimes it is intentional and sometimes not (crosstalk). I hope that this column, by mixing technology and general observations, is thought provoking and "couples" with your thinking. Most of the time I will stick to technology but occasional crosstalk diversions like this one may deliver a message closer to home.

Name Calling

► WHAT'S IN A NAME? A LOT! A name itself might not mean much but it can trigger expectations and stereotypes. In the United States we have red states and blue states depending on which political party has the majority vote. Similarly, when someone labels themselves on the basis of their political party affiliation (Republican, Democrat, Libertarian, Independent, etc.) others make assumptions how they think about the topical issues of the day.

Names are constructs that enable humans to characterize and build mental constructs and models about our world. Yes, they often lead to (over) simplification however without them the world might be too complex for one to comprehend.

If you have been in the electronic industry long enough, you probably have an opinion on "KGD". It is not a term widely known outside the world of semiconductors. I've heard others think it is a sister organization to the feared *Komitet gosudarstvennoy bezopasnosti* (KGB). The concept of obtaining **known good die** (KGD) probably strikes as much fear and loathing in a test engineer or product manager as the KGB did for Soviet dissidents.

There has been plenty of discussion on how to best obtain KGD over the years at test and integrated circuit related conferences. The annual Known Good Die Workshop started in 1994 to focus on the need for KGD driven mainly by the needs of multi chip modules (MCM) at that time. The KGD event is now managed by MEPTEC and was last produced in 2012 where the greater focus was on

KGD for 2.5 and 3D integrated circuit (IC) packaging. Hopefully after a hiatus this year, it will be back next year for the 20th anniversary.

Some may argue that true KGD are as mythical as unicorns. They are so elusive that finding a good definition is difficult. (What? There is no Wikipedia entry for KGD? Correct, only a passing mention in the Wafer Testing entry. Please feel free to create an entry.) For argument's sake, I will offer up my own definition:

A known good die (KGD) is a singulated (diced) integrated circuit that:

1. Has been tested and burned-in to a quality level that is sufficient to "know" the die meets all product specifications.

AND

2. There is a sufficient confidence will operate correctly and not cause failures when assembled, often irreversibly or without rework/repair possibilities, in a subassembly (MCM, 2.5/3D package, etc.).

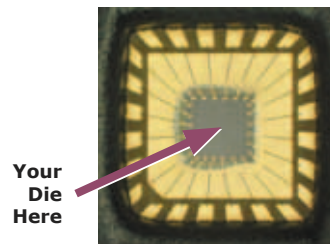
Needless to say there are several elements of this definition that are subjective. And an experienced engineer should immediately understand why the quest for KGD is extremely challenging if not downright frustrating.

In the late 1980's and early 1990's the KGD user community was a small group typically focused on high performance or high reliability applications such as supercomputing, military or space, implantable medical devices, and automobile safety systems. In our current era of More than Moore applications enabled by advanced 2.5D and 3D packaging, KGD is again a hot topic since the challenge is to integrate bare die and die stacks from multiple suppliers. Neither the integrator (packaging entity) nor the die suppliers want to cause the failure of the entire 2.5D/3D package therefore everyone will claim to ship KGD or known good (sub-)stacks (KGS).

The biggest change since the 1980's is the demise of vertically integrated electronic supply chains and most suppliers are focused on one part of the supply chain which requires them to obtain material from others. Business models for 2.5D/3D packaging may contain some version of the "blame game": if your part caused the entire subsystem to fail you need to pay for the cost of all the materials, assembly, and test. With con-

continued on page 14 ►

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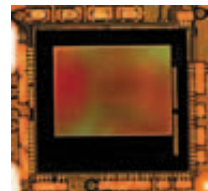
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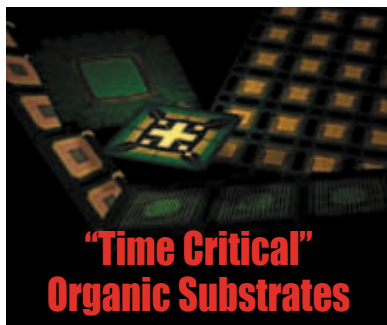
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COUPLING & CROSSTALK

▶ continued from page 13

stantly shrinking gross margins, a supplier certainly doesn't want to absorb the cost of their "failing" part let alone reimburse others therefore the emphasis on claiming KGD/KGS status. And the cost of the integrator or end product company to perform the root cause analysis (RCA) to determine fault is neither trivial nor inexpensive. In some cases, the RCA may be inconclusive or the cost exceed the value of the failing material.

Since KGD are not only elusive but problematic, what can be done to enable electronics to advance? This is a topic that I have discussed often with my colleagues in the Test & Test Equipment Technology Working Group (TWG) of the International Technology Roadmap for Semiconductors (ITRS). We are considering a change in the upcoming roadmap to be published at the end of this year. Though only the roadmap as published by the ITRS is the official opinion of the ITRS team, I feel it is worthwhile to share this thinking.

The change under considered is to **replace the term "Known Good Die" with "Not Known Bad Die" (NKBD)** or perhaps "Probably Good Die" (PGD). This is intended to be **more than a semantic change and to force a change in thinking.** Today the downstream user of a die believes it is good, based upon the previous testing. In reality it is very difficult to exhaustively and economically test the die to the full range of specifications. Sometimes the only way to completely test a die is through destructive testing. What typically happens is that a given device passes all the reasonable (and often economical) tests and is shipped having not been found to be bad.

With this shift in terms, the downstream user – die stack integrator, assembler of multichip modules, system designer, etc. – needs to consider how to build subsystems and systems that can be diagnosed for both materials (bad die) and assembly issues. These (sub)systems **need to be re-workable, repairable, or disposable** (assuming the costs are low enough) in the factory and/or in the field since it cannot be guaranteed that all die are good or will remain so over their life. At the same time it would be well advised to consider how to build systems with greater fault tolerance and self-

repair as system complexity continues to increase.

This may sound like a new paradigm for integrated circuits, however dynamic random access memory (DRAM) suppliers have been operating with internal repair for many years. Modern DRAM would have a very low yield (some designs will intrinsically yield no parts) due to defect density versus the size of the die area and the very small feature size of the memory cell. Therefore, DRAMs are tested in the factory and defective bits are switched with spare memory cells using laser or electrical repair. This allows almost all of the DRAM die on a wafer to be used unless there are significant defects.

Even though Not Known Bad Die (NKBD) is a mouthful, it really is more descriptive and should prompt improved system thinking that considers the challenges of developing advanced semiconductors and systems. Let's clean up our language to communicate today's reality! Our job as designers, test engineers, product managers, and managers is to work with what we have – even if imperfect – not what we wished we had.

Want to throw out some names or add to this discussion? As always, I encourage your comments on my blog <http://hightechbizdev.com>. ♦

IRA FELDMAN (ira@feldmanengineering.com) is the Principal Consultant of Feldman Engineering Corp. which guides high technology products and services from concept to commercialization. He follows many "small technologies" from semiconductors to MEMS to nanotechnology engaging on a wide range of projects including product generation, marketing, and business development.





Figure 3. Pebble e-paper watch. Source: Pebble

confused about what their goals should be, so their motivation and inspiration is often lacking. This creates an additional opportunity for OEMs to create a dashboard that inspires consumers to actively use their products.

This market will evolve to a point where these mobile health devices will continuously measure and report biometrics to the cloud in a way that is completely passive to the user with minimal to no upkeep, while the patient interacts with their data via a dashboard on their smartphone.

One of the ways that these products are going to come to market is through Crowd Sourcing. The most popular Crowd Sourcing options are Kickstarter and Indiegogo, two websites that enable new technology to come to market with a known user base.

In 2012 over 18,000 projects were funded on Kickstarter, with \$320m USD pledged by 2.2 million people. The most successful launch on Kickstarter in 2012 was the Pebble, which raised \$10.3 million. Pebble is an e-paper watch that can run fitness apps (it comes with an accelerometer), is waterproof, and uses Bluetooth 4.0 to connect to a smartphone (see Figure 3).

When it comes to the human body and the environment, there are dozens of sensors that can potentially be used to improve healthcare. There are acoustic sensors (hearing aid improvement), chemical sensors (air quality indicators), electric sensors (magnetometers), humidity or moisture or weather sensors (bedwetting alarms, rain sensors), navigation sensors (gyroscopes), position and angle sensors (accelerometers, tilt, fall sensors), optical sensors (indoors or outdoors), pressure sensors (basketball game improvement), temperature sensors, proximity sensors (motion detection), etc. Each of these could be used to assist in day-to-day living for Aging in Place, improving a user's movement precision to assist in sports, or even improve a user's mental

health. Depending on the market, these sensors will be placed on different parts of the body, and different metrics will be used to determine the quality of movement and if a behavior change should or can be enacted.

This is the technology behind Big Data, one of those key terms being thrown around lately, but in the Healthcare Industry everything relies on MEMS being able to collect as much data as possible and turning it into something useful.

Healthcare is a critical issue worldwide. There are 860 million people suffering from chronic diseases, 400 million suffering from obesity, and 600 million suffering from aging-related issues. These numbers represent a large potential market for healthcare devices.

For more information on the healthcare market, read Semico's new report, Mobile Healthcare: New Technology for a Healthy Lifestyle at semico.com. ♦



Figure 4. Fitness/Activity and Mobile Wellness growth.

Source: Semico Research

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The Richard Desich

SMART

**Commercialization Center
for Microsystems**

at Lorain County Community College



Since the early days starting in the 1960's, MEMS (Microelectromechanical Systems) were virtually stand-alone devices and were attached/inserted into custom designed mechanical or standard IC packages. More recently however, MEMS are truly becoming systems (as the "S" in MEMS connotes). The integration of MEMS devices into packages of various shapes, sizes and materials along with signal conditioning electronics, power sources and networking (both wireless and connected) communications IC's are now considered to be the true application solution (see Figure 1).

The role of packaging/assembly and test (P/A/T) in the overall successful commercialization of MEMS (see Figure 2) has historically taken a back seat to device development. More recently however, the MEMS community is taking note of the importance and the value of P/A/T in the

creation of MEMS-based solutions. Additionally, it is well known that the packaging/assembly and test (P/A/T) of a MEMS-based solution can be as much as 60% or more of the total cost of the solution. This fact makes the consideration of the packaging strategy a very important and early part of the solution design process to achieve optimum cost and performance. Here we are, approximately a half-century later from the early days of MEMS packaging and many of the same materials and packaging strategies are still in favor by many suppliers.

Additionally, the MEMS community had traditionally focused on the establishment of an infrastructure to design and manufacture Silicon devices especially including the creation of MEMS Silicon foundries. It was relatively easy for MEMS developers to have their devices manufactured in foundries including those of research universities e.g. Cornell, Stan-

ford, University of California Berkeley and University of Michigan as well as at the scores of commercial foundries worldwide. However... what was needed was a mechanism to package the output of the foundries i.e. Silicon wafers into products that could be tested. The weak link here was the mechanism to do this work in a developmental format and thus provide the designer with a convenient and full-service facility to package, assemble and test the MEMS device. The Richard Desich Smart Commercialization Center for Microsystems (SMART) serves this highly needed and critical "bridge" function in the commercialization of a MEMS-based solution (see Figure 3).

OVERVIEW

The Richard Desich SMART Commercialization Center for Microsystems ("Desich SMART Center") is a microsystem packaging, assembly, and test develop-



The new 47,000 square foot Desich SMART Center facility is expected to be completed in Q-3 2013 and will house class 100 and class 1000 cleanrooms as well as an incubator office space for startup companies.

ment foundry. Located and part of Lorain County Community College in Elyria, Ohio, the Desich SMART Center develops manufacturable packaging integration solutions for customers developing next-generation microsystem products by leveraging world-class facilities and a highly experienced engineering team to accelerate product time to market.

The Desich SMART Center was formed through a collaboration between Lorain County, the State of Ohio Third Frontier Program, Cleveland State University's Wright Center for Sensor Systems Engineering, Lorain County Community College, and local philanthropy. The Center was created in response to a known technology gap in the region: as companies prepare to commercialize sensor technologies and MEMS for use in technologies across many major industries, they encounter a common hurdle in testing and packaging the products. This time spent represents 70 percent of the total cost of commercializing a technology and in there is no resource in the Midwest, or largely in the United States, to support this work.

The Desich SMART Center is centered around a core facility with end-to-end microsystem packaging capability supported by reliability test equipment and further augmented by software design tools and materials databases. Such a complete packaging line promotes efficient problem-solving in what is typically a multi-step, iterative process. A single facility to investigate and prototype manufacturing processes for microelectronic packaging reduces the risk of contamination and damage due to shipping to job shop vendors; it streamlines project time frames, communication, and error causality tracking. Other unique benefits accrue to potential users of the Smart Center's resources (see Figure 4). The primary objective of such a facility is determine a package design for a specific product application, providing a resource for down selecting options from current manufacturable processes as a customer weighs this against product cost and supply chain limitations.

In addition to capital equipment, the Desich SMART Center will help train technicians upon which companies can draw. In collaboration with local industry, Lorain County Community College is building out a two-year degree program in microsystems. When complete, this curriculum will train students to work in a variety of fields that employ microsystem

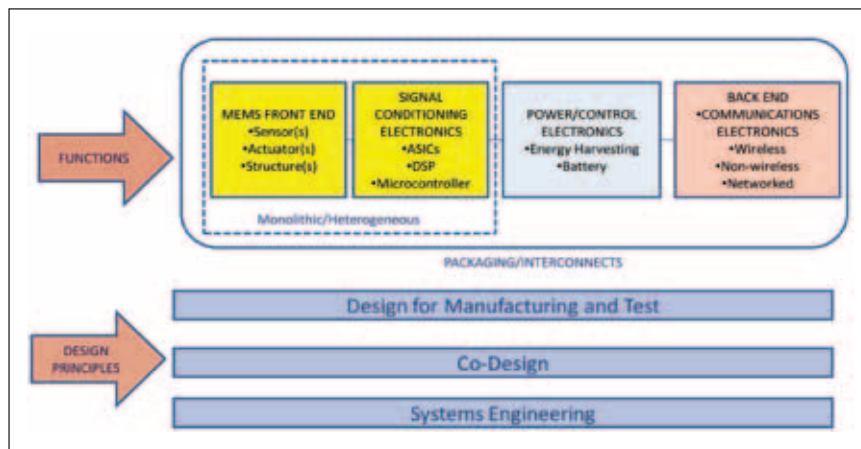


Figure 1. The key to a MEMS-based system solution is the packaging of all of its elements and the rigorous use of co-design principals to fully understand the complex interaction between the MEMS device, its associated signal conditioning electronics and the package.

Courtesy: Roger Grace Associates

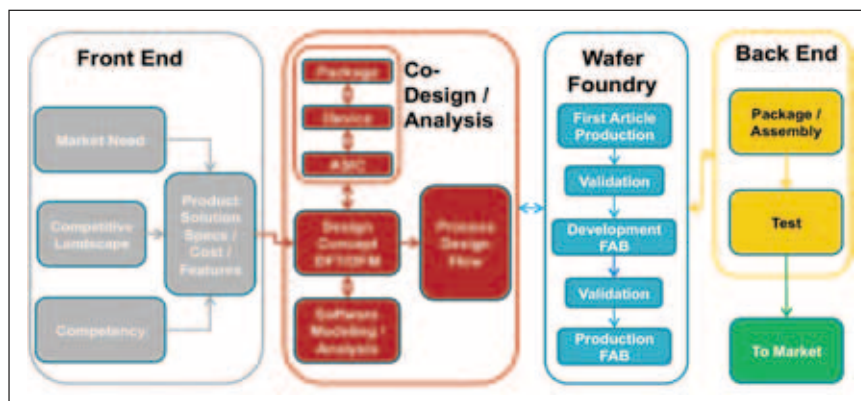


Figure 2. The MEMS commercialization process is complex and requires a great deal of front end coordination between package and interconnect designers, device designers, process engineers as well as test engineers if a successful outcome is to be realized.

Courtesy: Roger Grace Associates

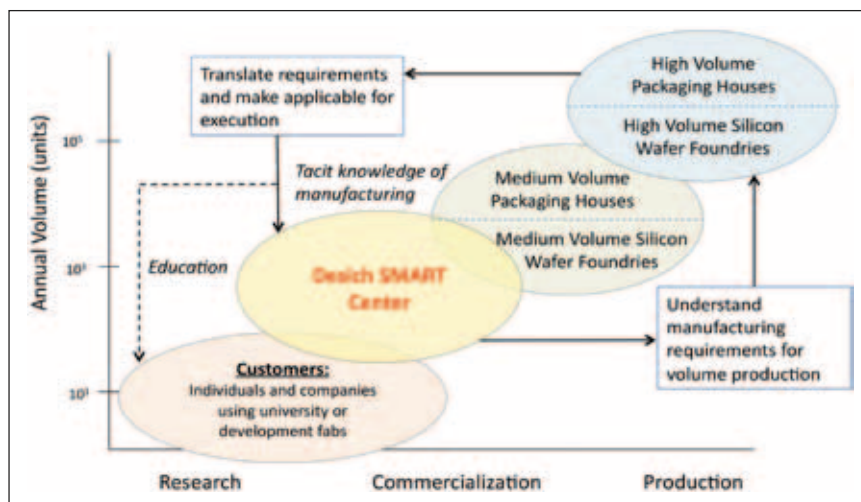


Figure 3. The Smart Center forms the long-time needed "bridge" between the producers of MEMS Silicon wafers and high volume packaging if successful commercialization of MEMS-based product is to be realized.

processing techniques. Already, there is a regional need for these types of skills, and the Center has created an independent study in microsystems packaging to fulfill near-term industry workforce needs.

Today, the Desich SMART Center is located in a temporary 1,800 sq. ft. class 10,000 cleanroom (see Figure 5) in the Entrepreneurship Innovation Center (EIC) on Lorain County Community College's campus while a new three-story, 47,000 sq. ft. facility is constructed adjacent to the EIC building. The first floor of the new facility will house state-of-the-market laboratory space, including class 1000 and class 100 cleanrooms. The equipment configuration establishes the facility as a "pilot plant" for manufacturing, thus facilitating the ease of transition from lab to manufacturing environment. The second floor is reserved for incubating space for startup companies as well as corporate incubating space to allow larger corporations a secure environment to innovate new product developments. The third floor will house the computer lab with software design tools, as well as wet labs that are available for rent.

TECHNICAL SERVICES PROVIDED

Advanced Packaging

SMART's Advanced Packaging tools are focused on the point when a client has a wafer for its microsystems design and needs to interface it to the real world. The Center's packaging, placement and coating tools were chosen for flexibility in a number of environments, substrate formulations and device geometries.

Feature	Benefit
1. "One Stop Shopping" for microsystems	1. Streamlines supply chain effort - reduces overall cost and time to market
2. Focus on microsystems technologies	2. Experts in the solution...analysis, design, manufacturing - enhances co-design approach
3. Non-profit...501c3	3. Provide best solution NOT maximize profit – engagement diversity
4. Collaborative partnership model	4. Maximize value add using trusted manufacturing partners
5. New equipment and facilities	5. Provide best possible product performance and quality

Figure 4. There are many unique features and related benefits that are unique to the Smart Center that are not currently available in the MEMS market when it comes to packaging, assembly and testing of MEMS-based solutions.

Reliability Analysis

In today's design world, reliability is paramount. This is true for mission-critical and life-critical applications and in every application area from consumer products to automobiles. The SMART Center's complete suite of reliability testing with a specialization in harsh environment testing help you design for reliability, whether your customer's operating theatre is in enemy territory, in a hospital, or in the consumer's hands.

With a full line of harsh environment testing equipment, SMART's tools can

provide clients with the data they need to get JEDEC or MIL-SPEC certification, pass FDA regulations, and design reliability into their products.

Inspection

SMART offers inspection and characterization tools on-site to enable troubleshooting during chip packaging or harsh environment reliability testing. In concert with life simulation software and access to the ASM materials database, these tools also support failure analysis investigations.



Figure 5. The Smart Center currently operates out of its temporary 1,800 square foot, class 10,000 cleanrooms with state-of-the art equipment to successfully support a broad range of packaging, assembly and test requirement of it many clients.

OTHER SERVICES PROVIDED

SMART can provide additional services to support clients with differing program needs on a case by case basis. Clients benefit from SMART's technical and facility resources as well as the offerings from a qualified "web" of regional suppliers.

Project Management

SMART's qualified engineers and technicians can work with clients on their microsystems packaging, testing, and analysis needs. Services range from basic tasks like die cutting, wire bonding and test implementation, to advanced test design and packaging engineering programs.

Microsystems Courses, Workshops and Seminars

SMART provides practical industry education in microsystems packaging, testing, characterization and analysis. Offerings range from general introductory classes to skill-based training using specific microsystems process tools. Classes are also offered by SMART's affiliate, ASM International. The Smart Center co-organizes and hosts at the Lorain Community College Campus the annual "Bio-medical Sensors and Sensors Conference". This two-day event brings together an international mix of leading researchers and developers to discuss some of the more interesting implementations of these devices and to address some of the more significant emerging biomedical sensing technologies. The 2013 program had over 160 attendees from international academia and industry. (www.biomems2013.com)

Fab Lab Access

The Fab Lab at Lorain County Community College provides a variety of rapid prototyping tools to create a wide variety of objects. Dedicated and commercial-only lab time is available to SMART partners, along with prototyping services.

On-Site Office Space

In addition to a no-charge common area with wireless internet and individual workspaces, SMART offers space option to make user organizations more productive. Secure office space (up to 500 sq. ft.) offers privacy for skunk works operations and easy SMART lab access.

		Wafer and Die Prep					Package Assembly				Testing				Reliability			
		Cutting	Wire Bond	Wire Die	Die Attach	Die Attach	Wire Bond	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach	Die Attach
MEMS & Sensors	HQ Sensor																	
	MEMS Gyro																	
	ICU Glucose Sensor																	
Micro-Electronics	High Temp IC																	
	Microwave Device																	
	Electro-photo Device																	
Materials	eWLP																	
	Thermal Management																	
	PV Devices																	

Figure 6. The Smart Center has demonstrated successes in a broad range of MEMS packaging, assembly and test facilities on a diverse range on MEMS projects including device encapsulation, reliability and failure analysis studies and environmental testing.

CASE/APPLICATION STUDIES

The following is a sample of some of the projects that the Smart Center has undertaken for its many satisfied clients. Figure 6 provides an overview of activities to date.

High Temperature IC's

- "on demand prototypes" with off the shelf lidded ceramic packages
- Initial request required process development
- Assisted in creating solution with non-optimized wafer layout and first packages
- Turn-around time with current process is one day

Package Assembly for Sensors and Actuators

- Optimizing customer's manual assembly of prototypes with proven manufacturable processes that increase performance and yield
- Examples: transfer hand soldering to aluminum wedge bonding, developing gold ball bond process for thermally isolated die, two-sided assembly process using pin dip interconnect

Sensor Encapsulation for Liquid Environment

- Process development with encapsulation materials for sensors e.g. Parylene, silicone
- Evaluate mechanical properties using pull testing to define manufacturing specifications
- Performance studies before and after reliability testing

Reliability Studies of Microelectronics Assemblies

- Run reliability tests on customer-provid-

ed components such as HAST, thermal-humidity cycling, high temperature storage, and biased 85/85

- Conduct failure analysis with acoustic microscopy, pull testing, interferometry, probe testing and optical inspection

SUMMARY

The Smart Center has been created to serve the microelectronics industry and to act as a provider of education to local Northeast Ohio students as well as a creator of jobs for its community. The role of the Center is to provide a developmental packaging, reliability and test capability that will act as a "bridge" to this barrier that existed in the industry for quite some time. The Lorain County Community College management in conjunction with several economic development organizations in Ohio are confident that the Smart Center will successfully accomplish its goals and serve both the microelectronics industry at-large as well as its local Northeast Ohio community.

For more information please contact Mr. Matt Apanius, Smart Center Director at matt@smartmicrosystems.com or go to www.smartmicrosystems.com. ♦

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LED Technology, Packaging & Test: *A Primer*

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1. Introduction

A LED, short for Light Emitting Diode, is a semiconductor p-n junction light source. Nicholas Holonyak, Jr. (b. 1928) is generally credited with creating the world's first usable LED in 1962 while working as a Consulting Scientist for General Electric. Since then, LED technology has seen numerous significant advances. The earliest commercial deployments of LEDs were in watches, calculators and signage- i.e. in indicator applications. Light output from these LEDs was very low and unsuited for general lighting. In the 1990s high power LED technology was developed by several research teams across the world, and ushered in the era of solid state lighting.

Table 1 summarizes historical developments in LEDs and their applications over the years.

Figure 1 shows a roadmap/forecast projection for packaged LEDs from Yole^[1,2]. By 2020, global packaged LED revenues are expected to reach US\$27B, of which General Lighting is roughly three times the size of all other categories together.

2. How Do LEDs Emit Light?

LEDs are formed by bringing two 'oppositely' doped semiconductor regions together to create a p-n junction. In the p-n junction, the n-side has an excess of negative charge carriers (electrons) while the p-side has an excess of positive charge carriers (also known as holes). These regions are separated by a thin zone called the depletion zone. When a LED is forward biased, i.e. the p- junction is connected to a positive voltage potential and the n- junction to ground, electrons move from the n-side to the p-side while holes move from the p-side to the p-side and combine in the depletion zone. These combinations and recombinations are radiative and result in the generation of light (see Figure 2).

The color of light (i.e. the wavelength) emitted by a diode is dictated by the band-gap energy. Figure 3 shows band-gap energies and wavelengths for two common semiconductor materials in use

1962	First (Red) LED	General Electric (N. Holonyak, Jr.)
1971	First LED powered calculator	Mostek, Texas Instruments
1972	Yellow, Red, Red-Orange LEDs	Monsanto Chemical Company (M. G. Craford)
1975	First LED Calculator Watch	Hamilton Pulsar
1977	First LED Display Screen	R & D, James Mitchell
1993	First Blue LED	Nichia (Shuji Nakamura)
1990s	LEDs replace incandescent bulbs in flashlights	
1999	First optical LED Mouse for PCs	Microsoft
2000s	High Flux packages for automotive, backlight applications	Philips Lumileds, Cree, Nichia
2012	Organic LED HDTV	LG
2012	60W & 100W Incandescent Replacement	Philips Lumileds/ Osram Sylvania

Table 1. LED History

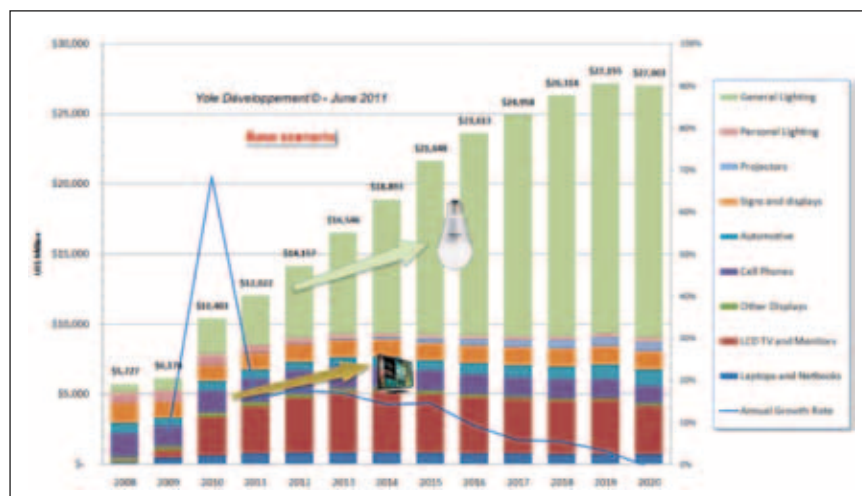


Figure 1. Global Packaged LED Revenues.^[1,2]

today. InGaN or Indium-Gallium-Nitride is used for violet, blue and green LEDs and InGaAlP (Indium Gallium Aluminum Phosphide) is used for green, yellow, orange or red LEDs. Other combinations from the III-V semiconductor family are also possible, as Figure 4 shows.

3. LED Packaging

Fabrication of an LED begins with a

substrate on which several epitaxial layers are grown. Generally speaking, such layers are no more than a few atoms thick. Numerous processing steps later, the die wafer is ready for singulation. Wafer scribe-and-break or traditional wafer saw are common techniques used to separate the dies. The resulting dies either have lateral terminals (interconnect pads) or top-and-bottom contacts.

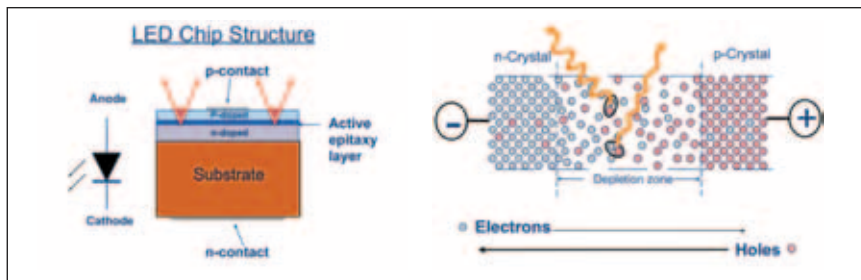


Figure 2. LED Basics. [3]

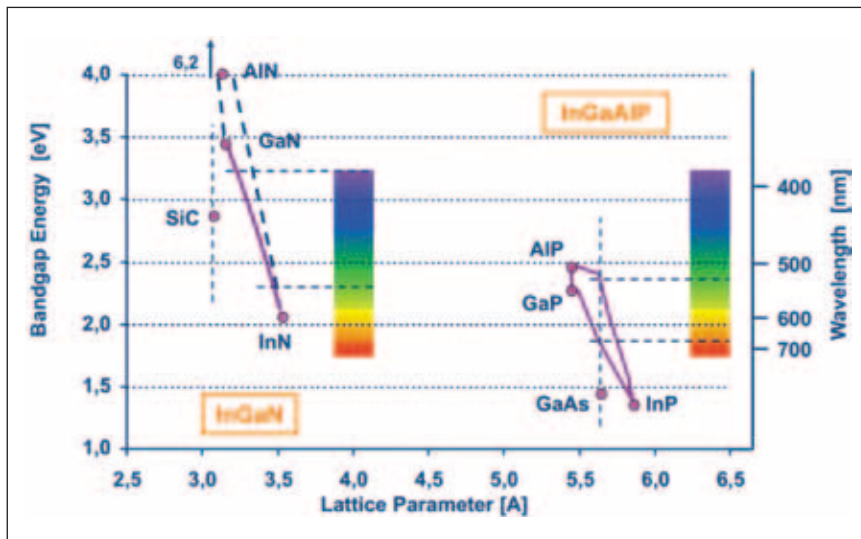


Figure 3. Material Systems In Use for LEDs. [3]

Group IIIA	Group IVA	Group VA
5 B Boron 10.811	6 C Carbon 12.0107	7 N Nitrogen 14.006
13 Al Aluminum 126.981	14 Si Silicon 28.0955	15 P Phosphorus 30.973
31 Ga Gallium 69.723	32 Ge Germanium 72.61	33 As Arsenic 74.921
49 In Indium 114.818	50 Sn Tin 118.710	51 Sb Antimony 121.760
Base Elements		
P-Type Dopants		
N-Type Dopants		

Figure 4. III-V Family For LEDs. [4]

Either a single such die or an array of such dies is connected to an optional submount, which in turn is connected to a chip carrier or package substrate. Borrowing terminology from semiconductor interconnect, the connections between the dies and

the optional submount could be labeled 'L1' (or Level 1), and between submount and the package substrate as 'L2' (or Level 2). The package substrate in turn can have interconnect to attach it to the application main board, and this level of interconnect is labeled 'L3' (or Level 3). If the package configuration has dies directly assembled onto the package substrate, the L2 interconnect serves the role of L3.

Materials used for the submount/package

age substrate can include metal-core PCB constructions (MCPCBs), ceramics such as Aluminum Nitride with top/bottom surface routing, i.e. direct bonded copper (DBC), or custom reflector constructions. In addition to this constructional complexity, packaged LEDs often need ESD protection, and this is accomplished by incorporating ESD diodes into the package configuration.

There are literally hundreds of non-standard package configurations in the LED industry, in contrast with the semiconductor world where there is much standardization on body size, IO count and design rules on manufacturing. Figure 5 shows just a few examples of LED packages/emitters in production today [2].

In finished goods form, LEDs can produce various colors such as red, yellow, blue, green or other. To produce white light for use in general lighting applications, there are several techniques in use. One such technique is where the package has red, green and blue diodes; another uses yellow and blue diodes; another uses blue diodes to pump phosphors; and yet another uses an ultraviolet LED to pump a three phosphor system, as shown in Figure 6.

4. Human Vision & Spectral Sensitivity

4.1 How Human Eyes Work

The posterior wall of the human eye (Figure 7) has a region called the retina, which is composed of millions of photoreceptor cells called rods and cones. Rods and cones are essentially specialized neurons that are responsible for the sensory aspect of vision.

Rods, numbering roughly 120 million, are responsible for black/white vision, shape and contrast in the field of vision. Cones, which number roughly 6 million, are photoreceptors that are responsible

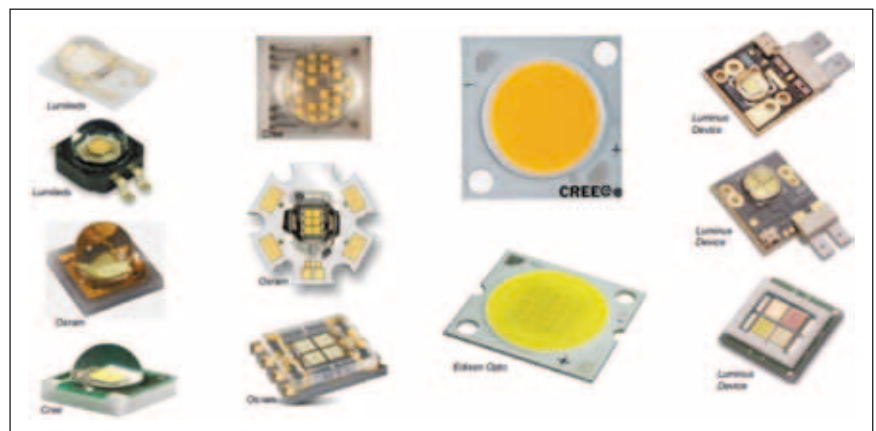


Figure 5. A Selection of Packaged LEDs, Typical For High Power Applications. [2]

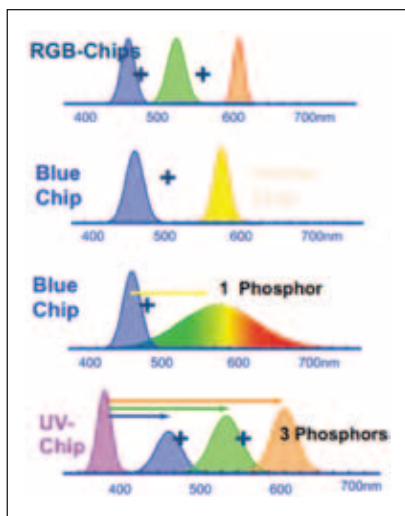


Figure 6. Prior Art to Produce White Light with LEDs. Emitted Wavelength on x-axis.^[3]

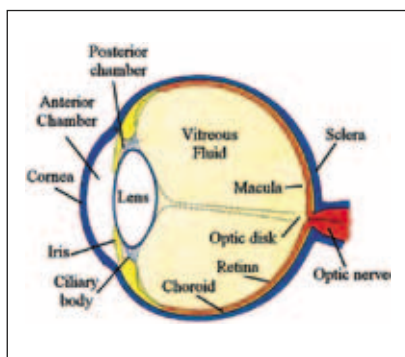


Figure 7. The Human Eye.^[5]

for color perception and are sensitive to 420nm (blue), 534 nm (green) and 564 nm (red) wavelengths.

When a photon from an irradiated object lands on the retina, its energy initiates a series of complex chemical reactions (see Figure 8) resulting in the transmittance of a neural signal that is relayed to the brain via the optic nerve.

4.2 Photopic & Scotopic Responses

The human eye does not have uniform sensitivity across all illumination wavelengths. In fact, under high illumination (equivalently, day light) conditions, the human eye is most sensitive to 555nm while at low illumination (equivalently, night light) conditions it is most sensitive to 507nm. The sensitivity of the eye to various wavelengths under these illumination conditions is categorized as the photopic ($V(\lambda)$) and scotopic response ($V'(\lambda)$) respectively. Using the concept of a 'Standard Observer', i.e. an averaged observer over many repeated tests, the CIE

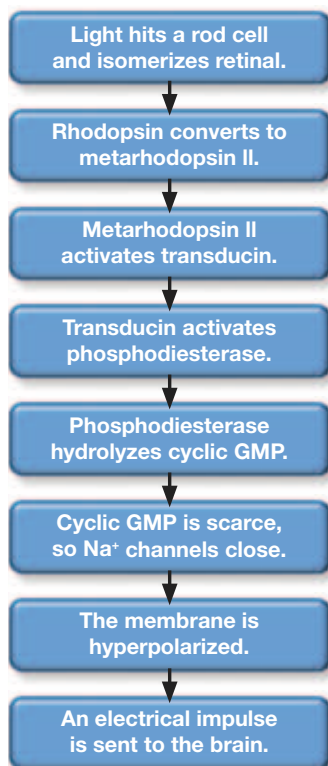


Figure 8. Photoreceptor Chemical Reactions Involved in Human Vision.^[6]

(Commission internationale de l'éclairage) has published standard spectral response curves for the eye shown in Figure 9. The photopic spectral response, for example, captures the fact that at high brightness conditions, the human eye is roughly 20 times more sensitive for yellow/green light (555nm) than it is for red light (670 nm) or blue light (450 nm). In addition to photopic and scotopic responses, another characteristic of the human eye exists (the *mesopic* response), but is not covered here.

A simple example serves to explain the role these spectra play in human being's visual perception of objects. Figure 10

shows the radiant spectrum of a candle (the radiant spectrum being the unmodulated or "real" spectral distribution of the power from source as a function of the wavelength). This spectrum peaks in the infrared spectrum, and in the visible spectrum peaks at red wavelengths. If the human spectral response were flat, an observer would see the color of the candle as red. In reality the luminous flux perceived by the eye (shaded region in the figure) has a peak near 580nm, resulting in a yellow perception of color^[8].

5. Quantitative Measures of LED Performance

5.1 Radiometric Parameters

The *radiant power* of an LED source, denoted Φ_e , is the total power of emitted electromagnetic radiation, including visible/UV/infrared regions and is measured in watt (W). The radiant power, as may be expected actually has a spectral distribution (as a function of wavelength), and it is easier to work with the *spectral radiant flux*, ϕ_λ defined as the derivative of the radiant power distribution w.r.t. the wavelength. Frequently, the *spectral radiance*- also known as spectral radiant flux *density* i.e. the derivative of the radiant power distribution *per unit area* (W/mm^2) w.r.t. the wavelength (nm) is also used (see Figure 11).

Monochromatic sources have a single peak in the radiant flux spectrum, while non-monochromatic sources have a distribution. Examination of the spectral radiant flux distribution gives more information than just the associated radiant power, since the spectrum highlights the energy distribution among the various wavelengths.

In practice one can readily relate the optical power to the photon rate through Planck's equation. Thus 1W of optical power for a source that produces mono-

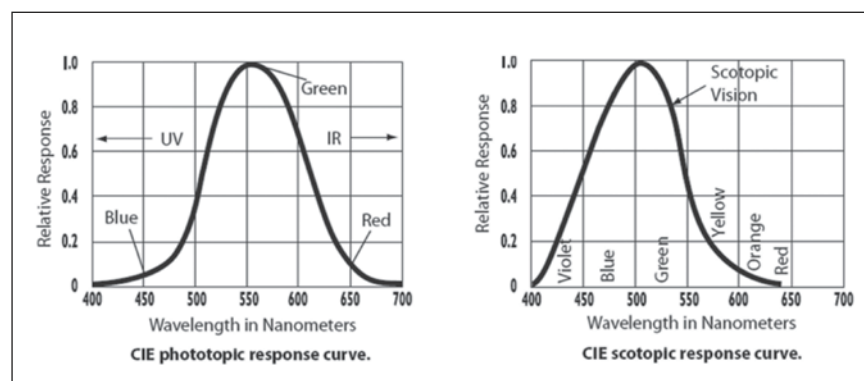


Figure 9. Photopic & Scotopic Spectral Responses.^[7]

chromatic light of wavelength 630 nm equates to 3.2×10^{18} photons/sec.

Radiometric characteristics of a light source are absolute, i.e. unaffected by perceptive characteristics or modulation of the human eye.

5.2 Photometric Parameters

The *luminous flux* of a source is its spectral radiant power, weighted by the (photopic) sensitivity of the human eye. It is measured in Lumen. Formally, the luminous flux is the weighted integral of the radiant power over the visible spectrum, as below:

$$\Phi_V = 683 \int_{380}^{780} \Phi_e V(\lambda) d\lambda$$

A related parameter is the *luminous intensity*, which is the intensity of light emitted in a particular direction, formally defined as:

$$I = \frac{d\Phi_V}{d\Omega}$$

Luminous intensity is measured in Candela, denoted cd.

Example 1: A 10 mW laser pointer operates at a wavelength of 700 nm. What is its lumen output?

Answer: $683 \times 0.010 \times V(700\text{nm}) = 683 \times 0.010 \times 0.004102 = 0.03 \text{ Lm}$

Example 2: A 5 mW laser pointer operates at a wavelength of 550 nm. What is its lumen output?

Answer: $683 \times 0.005 \times V(550\text{nm}) = 683 \times 0.005 \times 0.995 = 3.4 \text{ Lm}$

Notice that the laser source in the second example is half as much optical power, but produces 100X lumen (visible light) output.

5.3 Efficiency Parameters

The energy efficiency of an LED, termed η , is defined as the ratio of the optical power (i.e. wattage equivalent of the power in the visible spectrum) divided by the input electrical power. Figures of merit such as the *energy efficiency* give a firm basis to compare various light sources from their conversion efficiency standpoint: most incandescent lamps, for example have η ranging between 4-5%, fluorescent tubes have η ranging between 27-29%, sodium vapor lamps between 30-40%, and the blue LEDs used to create white LED sources measured cold have η in the range >50%.

The *efficacy* of an LED is the photometric flux it emits divided by the electrical power driving it, and has units of

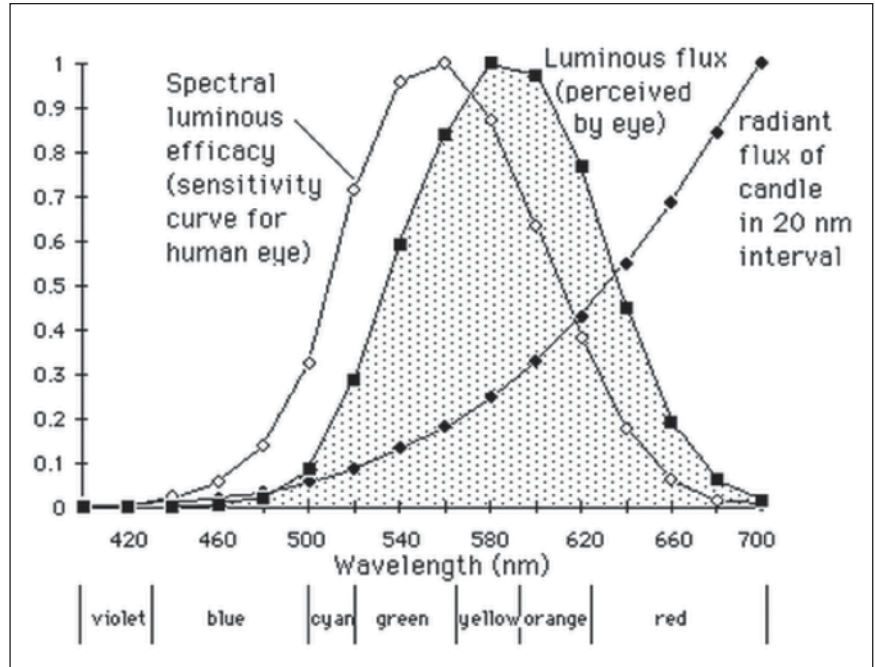


Figure 10. Photopic Spectral Response, Candle Radiant Spectrum & Perceived Spectrum. After [8].

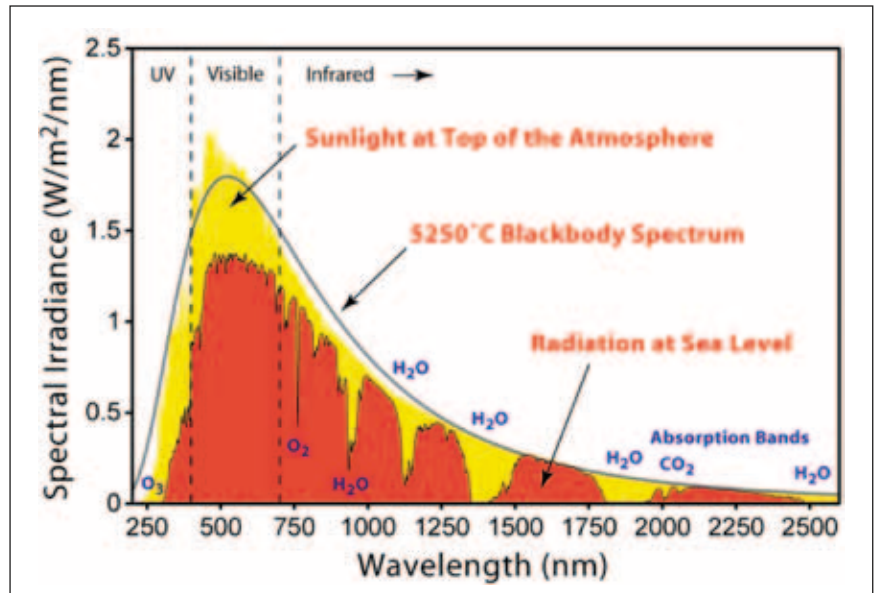


Figure 11. Spectral Radiant Power Density for the Sun. After [9].

Lm/W. As an example, if an LED package produces 80 lm at 3V and at a drive current of 200 mA, its efficacy is $80/0.6 = 133 \text{ Lm/W}$.

6. Color Science Basics

6.1 Color Coordinates & Color Temperature

Two key concepts related to solid state lighting, i.e. Color Temperature and Color Rendition are introduced in this section.

The human eye has three types of cones (S, M and L) which have different absorption characteristics for impinging photons (see Figure 12).

Using these absorption spectra, termed $r(\lambda)$, $g(\lambda)$ and $b(\lambda)$ three unique quantities for an emission spectrum $I(\lambda)$ can be calculated, viz.,

$$R_O = \int_{380}^{780} I(\lambda)r(\lambda)d\lambda$$

$$G_O = \int_{380}^{780} I(\lambda)g(\lambda)d\lambda$$

$$B_O = \int_{380}^{780} I(\lambda)b(\lambda)d\lambda$$

While these are convenient to characterize the spectrum, for purposes of standardization it is found better to use stimulant curves $x(\lambda)$, $y(\lambda)$ and $z(\lambda)$ that are linear combinations of the baseline $r(\lambda)$, $g(\lambda)$ and $b(\lambda)$. Accordingly, the equivalent characteristic terms are:

$$X = \int_{380}^{780} I(\lambda)x(\lambda)d\lambda$$

$$Y = \int_{380}^{780} I(\lambda)y(\lambda)d\lambda$$

$$Z = \int_{380}^{780} I(\lambda)z(\lambda)d\lambda$$

Now these three terms can be uniquely reduced to two by defining:

$$x = \frac{X}{X+Y+Z}$$

$$y = \frac{Y}{X+Y+Z}$$

and noting that by defining a 'z' similarly, it is adequate to characterize the color by only specifying (x,y) since then $z = 1-x-y$. The CIE adopted this (x,y) nomenclature of color designation/quantification into a standard in 1931. In 1976, this system was replaced by an entirely equivalent system of coordinates (u' , v') which is in use to this day (see Figure 13). Shown there in exaggerated form are example MacAdam ellipses- regions of the (u' , v') space where in principle the eye cannot distinguish color. In modern LED/solid state lighting manufacturing practice, one key element of the finished goods is color consistency, and manufacturers often bin product into color zones 3-MacAdam ellipse wide, 4-MacAdam ellipse wide etc during final sort.

The right hand side of Figure 13 shows

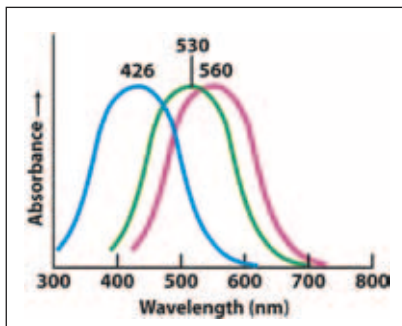


Figure 12. Cone Absorption Spectra in the Human Eye. After [10].

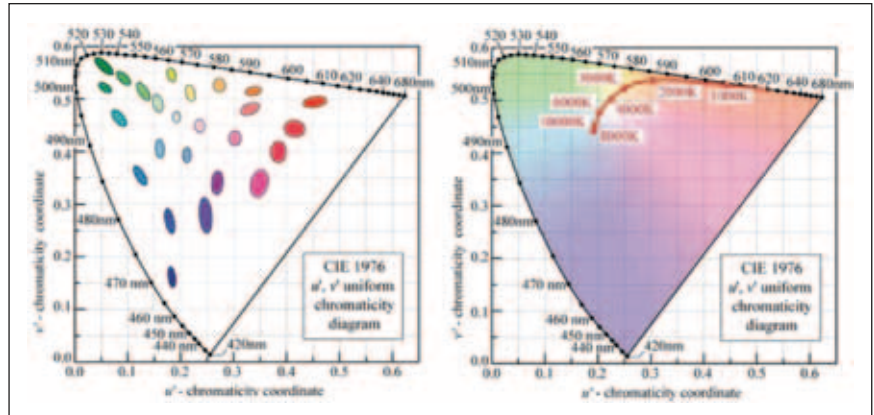


Figure 13. CIE 1976 (u' , v') Chromaticity Chart: Left, showing MacAdam Ellipses, Right: Showing Black Body Color Temperature Locus. After [11].

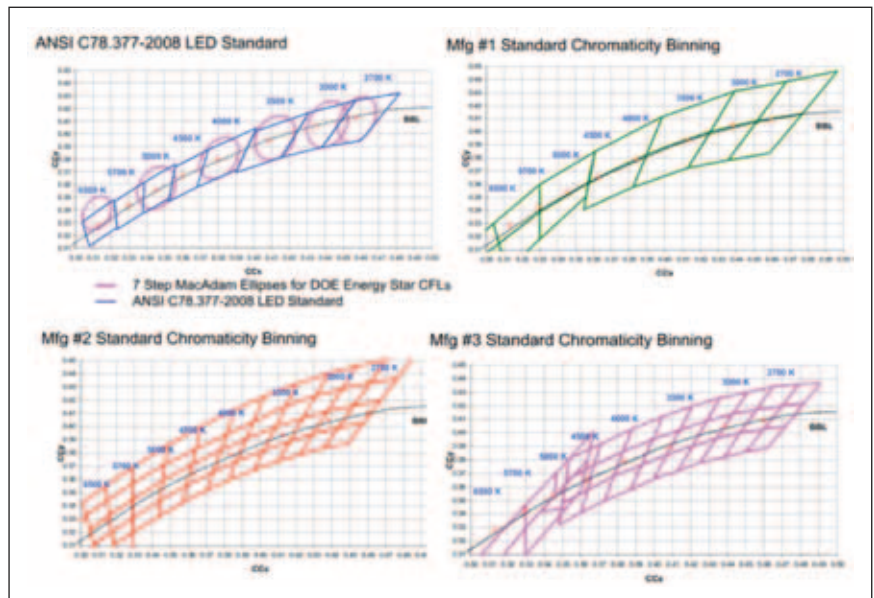


Figure 14. Different Manufacturers Have Different Binning Practices. [4]



Figure 15. Panel Color Samples for the CRI Test. After [12].

Color Temperatures- for instance a 3000K light would be classified as 'warm white', and a 8000K source as 'cool white'. LED manufacturers also bin parts based on color temperature in production, using ANSI bin definitions as a basis. However there can be significant deviations from the ANSI definitions also (see Figure 14) [4].

6.2 Color Rendition

In addition to the color coordinates and color temperature, which define the characteristics of the light source, there is one key parameter that is related to the quality

of color rendition in the irradiated medium (i.e. the object on which the produced light falls or illuminates). The CIE denotes this parameter formally as the Color Rendition Index, or CRI.

The standard test color method for color rendition uses eight standard color samples and size special color samples (see Figure 15). For a given color sample, the chromaticity under the source in question is compared to that under a reference source of equal color temperature. The difference in the color measurement is then mathematically adjusted and subtracted from 100 (the

perfect score) to give the individual score R_i for a given panel [12]. The principal metric, CRI is then obtained as the numerical average of the R_i for the first eight standard colors. A score of 100 indicates that the LED/source in question renders colors in a manner identical to the reference source. Generally speaking, CRI scores in the 70s are suitable for general interior lighting. High CRI scores in the 90s would be considered as ‘excellent’ in this category.

LED companies publish CRI values for various emitters they manufacture, in addition to color temperature as part of their standard datasheet format.

7. Interpreting Manufacturer Datasheets

When sizing up candidate LEDs for an application, at first glance it appears that comparisons between LEDs from different manufacturers should be straightforward – especially given the published datasheet metrics such as color temperature, CRI, efficacy, lumen output and maintenance. The reality is that stock datasheets from manufacturers list these metrics at specific carefully controlled conditions (e.g. at room temperature, as opposed to being tested hot; at specific bias currents, and so on). Without analyzing how LEDs behave at the conditions of interest to the application can lead to poor performance and potential business risk.

A recent article by Philips Lumileds [13] illustrates the case in point. The example application in question is the design of a single-LED based desktop lamp with the highest possible light output while having no more than 30% of output degradation over 50K hours of operation. To this end, candidate LEDs from four real-world manufacturers (see Figure 16) are considered as candidates. Nominally, it ‘appears’ that MFR3 is the most promising with the largest lumen output.

These data are not specified at the same operating current. With the stated goal of maximizing the flux, suppose the LEDs are all compared at the drive current of 700 mA. Figure 17 shows the current-normalized data, based on the individual LED flux/current characteristics.

From Figure 17 it is evident that MFR3 is no longer the front runner from a lumen output standpoint. That being said, the comparisons between the LEDs is not yet on a fair basis since the operating temperature hasn’t been accounted for. This is done using separate temperature derating tables that are also published by the LED

LED	Datasheet Min. Flux	Datasheet drive current	Datasheet test temp	Datasheet test time
MFR 1	91 lm	350 mA	T_A 25C	25 ms
MFR 2	107 lm	350 mA	T_J 25C	25 ms
MFR 3	130 lm	700 mA	T_A 25C	25 ms
MFR 4	100 lm	350 lm	T_{Pad} 25C	25 ms

T_A : Ambient Temperature
 T_J : Junction Temperature
 T_{Pad} : Solder Pad Temperature

Figure 16. Example Specifications for LEDs. [13]

Manufacturer	Datasheet Min. Flux	Normalize to drive current	Normalized Min. Flux @ 700 mA	Datasheet test temp	Datasheet test time
MFR 1	91lm	700 mA	164 lm	T_A 25C	25 ms
MFR 2	107 lm	700 mA	182 lm	T_J 25C	25 ms
MFR 3	130 lm	700 mA	130 lm	T_A 25C	25 ms
MFR 4	100 lm	700 mA	165 lm	T_{Pad} 25C	25 ms

Figure 17. Light Output from LEDs at Normalized 700 mA Drive Current. [13]

Manufacturer	Datasheet Minimum Flux	Actual Drive Current	Normalized Min. Flux @ 25 C	Datasheet T_J max.	Operating T_J (calculated) @ 25CA, Rth50K/W	Determine Flux De-rating Factor	Actual Flux
MFR 1	91 lm	700 mA	164 lm	145C	135C	72%	118 lm
MFR 2	107 lm	700 mA	182 lm	150C	128C	78%	142 lm
MFR 3	130 lm	700 mA	130 lm	125C	141C		
MFR 4	100 lm	700 mA	165 lm	150C	130C	81%	133 lm

Figure 18. Accounting for the Operating T_J . [13]

manufacturers as part of the datasheet. The results appear in Figure 18; the 28% degradation in flux output for MFR1 is noteworthy under these conditions. All-in-all, MFR2 and MFR4 appear the most promising.

The final requirement of the design was a minimum of 70% lumen maintenance over 50K hours of operation. By consulting the lumen maintenance charts for each LED, data on operating life are obtained and shown in Figure 19.

It is clear from Figure 19 that the LED

designated MR4 is the only one that can meet the various conditions imposed. As this example analysis has shown, rigorous sizing of LEDs for candidate applications involves more than just using top-level datasheet lumen specifications.

8. US DOE CALiPER Program

“For the other nine SSL products [out of 15 tested], information published by the manufacturers regarding product output and/or efficacy overstated performance (by factors ranging from 30 – 600%).” [14]

“For a number of products, manufacturers publish the LED luminous efficacy (lamp efficacy) and expected lumen output levels based on the LED lamp performance. This could be misleading because the actual measured luminaire efficacy is far less than the LED lamp efficacy (on average, about 1/3 of the LED luminous efficacy).”^[15]

Solid state lighting technologies continue to evolve at a fast pace today. Products arriving on the market today have a wide range of performance. There is a compelling need to have reliable, unbiased product performance information so there is a fair basis to compare options, and to further foster strategic R&D efforts in solid state lighting. To this end, the US DOE has a Program called CALiPER: *Commercially Available LED Product Evaluation and Reporting* which supports testing of a wide array of SSL products available for general illumination. The US DOE allows its test results to be distributed in the public interest for non-commercial, educational purposes only. Additional details may be found at the CALiPER website, <http://www1.eere.energy.gov/buildings/ssl/caliper.html>.

9. Closing Remarks

Worldwide, there is a push to replace conventional energy inefficient light sources with solid state lighting. Considering incandescent bulbs alone, Brazil and Venezuela started the phase-out in 2005, and the European Union, Switzerland, and Australia started to phase them out in 2009. Likewise, other nations are implementing new energy standards or have scheduled phase-outs: Argentina, Russia, and Canada in 2012, and the United States and Malaysia in 2014^[16]. Some LED manufacturers have now started to publish handy guides (see Figure 21) that show equivalent energy efficient alternatives. The solid state lighting revolution based on LED technology holds incredible promise to reshape the lighting landscape in an increasingly clean-tech, green-tech world. ♦

Manufacturer	Calculated Lumens	Lumen Maintenance L70 Claim	Datasheet T _j max.	L70/50kh conditions	Actual Operating T _j (calculated)	Calculated current to achieve lumen maintenance	Final Calculated Lumens
MFR 2	142 lm	50,000 hours	150C	T _j ≤ 85C T _A = 25C	128C	407 mA	107 lm
MFR 4	133 lm	50,000 hours	150C	T _j ≤ 135C & if < 700 mA T _A N/A	130C	700 mA	133 lm

Figure 19. Incorporation of Lumen Maintenance Data.^[13]

	Type of Fixture	Light Output (lumens)	MFG's Published Efficacy (lm/W)	DOE Measured Efficacy (lm/W)
CPTP-06-01	Downlight	193	40	12.82
CPTP-06-02	Under-Cabinet Light	166	55	16.07
CPTP-06-03	Downlight	298	45	19.3
CPTP-06-04	Task Light	114	36	11.6
CPTP-06-05	Outdoor Area Light	2638	24	23.9

Figure 20. Examples of Disparity Between Published & Actual Lumen Efficacy.^[15]



Figure 21. Bulb Replacement Guide.^[17]

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MEMS Need Comprehensive, Market-Ready Solutions

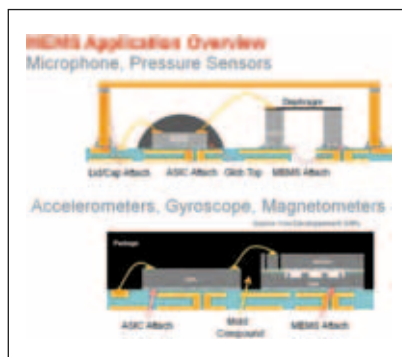
Shashi Gupta

Henkel Electronic Materials, LLC

MICROELECTROMECHANICAL systems – commonly known as MEMS – applications are on the rise. In fact, the MEMS market is currently outpacing overall IC market growth at a rate that is twice as fast and is expected to be a \$20B US market as early as 2017. Why the uptick in MEMS use? The consumer (primarily handheld) and automotive markets hold the answer for now, but other market sectors such as medical, for example, are also beginning to incorporate MEMS devices.

Consider that today the average smartphone contains approximately eight to ten MEMS – a number which is projected to grow in the coming years – and one gets a sense for the breadth of MEMS applications. Scroll speed on the smartphone touchscreen, screen orientation when the device is turned, noise-cancelling microphones, anti-shaking feature in cameras and much more – all are MEMS. And, when it comes to automotive MEMS applications, the list is equally as long and includes tire pressure sensors, air bag deployment sensors, GPS systems, headlights that can detect the curve in the road, side mirror proximity sensors and more.

Certainly one of the primary drivers of MEMS growth is the functionality these system-in-package powerhouses deliver. But other important factors include the ability to reduce form factors and the speed with which new MEMS can be brought to market for a viable, technology-enhancing solution. MEMS can be classified into several categories, the most common of which are accelerometers, gyroscopes, magnetometers, microphones and pressure sensors. While all have different functions and applications, they share two common requirements: (1) time-to-market-speed



dictates success and, (2) stress reduction and reliability of the MEMS assembly is critical.

The ability to design, test and commercialize new MEMS devices quickly is critical to a MEMS manufacturer's market competitiveness. And, in order to meet the three to six month average cycle time, MEMS firms need to leverage proven materials solutions that are market-ready, market-tested and supported globally to facilitate multi-site design and manufacturing.

This is the Henkel advantage. With a full portfolio of materials for varying

processes from die attach to underfill to lid attach and glob top, Henkel's breadth of commercialized, proven materials in combination with a comprehensive global support structure, enable Henkel to quickly deliver materials off the shelf and around the globe for just about any MEMS application. Henkel's ability to provide multiple materials for quick evaluation and testing, along with the company's unmatched global infrastructure, ensures expert worldwide technical support. What's more, the broad portfolio of multiple MEMS materials (reference the below charts) helps simplify the supply chain, enabling a more streamlined approach.

Of course, quick time-to-market has to be coupled with excellent performance and, for MEMS that means low stress and high reliability. The calibration of a MEMS device determines the balance required for proper long-term function. But subtle changes in materials – delamination, shrinkage and warping – can impact the device configuration and

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SOLUTIONS PORTFOLIO	ASIC Attach or MEMS Attach	LidCap Attach
Non-Conductive Paste/Liquid Dispensed	LOCTITE ABLESTIK QMI 538NB LOCTITE ABLESTIK QMI 538NB LOCTITE ABLESTIK 2025D	LOCTITE ABLESTIK 3220 LOCTITE ABLESTIK 3128 LOCTITE ABLESTIK MC723
Non-Conductive-Print Film	LOCTITE ABLESTIK 8006NS LOCTITE ABLESTIK 6202CX LOCTITE ABLESTIK ATB-120US LOCTITE ABLESTIK ATBF-125E	NA
Conductive Paste	LOCTITE ABLESTIK 8290 LOCTITE ABLESTIK 2100A	LOCTITE ABLESTIK CE3920I ICP3920 LOCTITE ABLESTIK SR4 LOCTITE ABLESTIK 2030SC

SOLUTIONS PORTFOLIO	Glob Top	Underfill NCP	Mold Compound
Non-Conductive Paste/Liquid Dispensed	LOCTITE ECCOBOND EO1058 LOCTITE ECCOBOND UF 8828	LOCTITE ECCOBOND FP4549 (CUF) LOCTITE ECCOBOND FP4530 (CUF) LOCTITE ECCOBOND FP5201 (NCP) LOCTITE ECCOBOND NCP5208 (NCP)	LOCTITE HYSOL GR9810-1P (75um filler) & LOCTITE HYSOL GR9810-1PF (45um filler)



The smaller the device - the more solutions

No matter where you are or what your process requires, you can count on Henkel's expertise. Our unmatched portfolio of advanced materials for the semiconductor and assembly markets all backed by the innovation, knowledge and support of Henkel's world-class global team ensures your success and guarantees a low-risk partnership proposition.



Excellence is our Passion

Advanced Packaging Materials: Hitting the Hot Buttons

WHETHER YOU ARE TALKING about advanced wafer level packages (WLPs), 2.5D interposer or 3D ICs, the ability to achieve the fine features, low temperatures, low stress and high performance requirements to successfully manufacture these devices now rests firmly on the shoulders of materials manufacturers. This article identifies some material “hot buttons” and how Dow Electronic Materials is breaking through these limitations.

SnAg-Capped Cu Pillars

With mobile device manufacturers clamoring for higher density, fine-pitch ICs, a trend towards implementing Cu Pillar bumps capped with SnAg solder as an alternative to C4 solder bumps has emerged.

When selecting materials that will result in high-yield, reliable electroplated Cu Pillar and Cu μ Pillar capped structures, it is important to consider the interface between metal layers, particularly as Cu Pillar cap diameters shrink to μ Pillar dimensions ($<30\mu\text{m}$ diameter). Additionally, interfacial properties and intermetallic compounds (IMCs) must be understood and controlled.

In designing chemistries, Dow engineers place high importance on understanding the compatibility of the Cu and solder materials at an early stage of the development process. The company's current commercial offerings, INTERVIA™ 8540 Cu Pillar and SOLDERON™ BP TS4000 SnAg solder, have proven compatibility (Figure 1). Customer needs for finer geometries are driving further development work on next generation Cu Pillar and SnAg chemistries.

Dow has developed a new XP Formulation A Cu Pillar (Figure 1) that satisfies all key design criteria including highly uniform Cu Pillars (WID $<5\%$); a flat pillar profile (TIR $<5\%$); smooth surface morphology; and compatibility with SnAg capping (Table 1).

Additionally its companion XP SnAg formulation has demonstrated high speed plating ($>3\mu\text{m}/\text{min}$); highly uniform SnAg

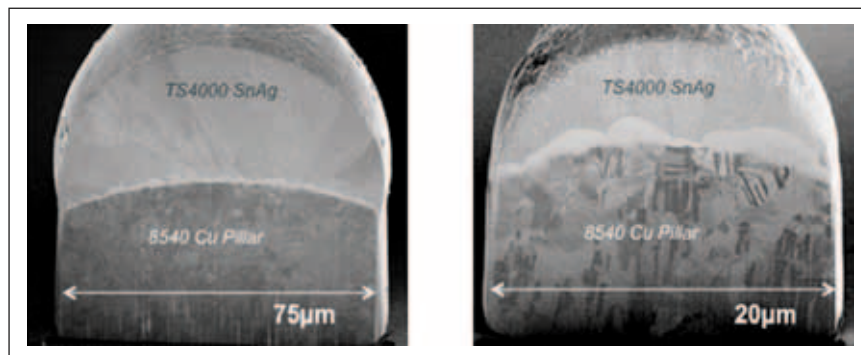


Figure 1: Left, Cu Pillar with SnAg cap. Right, Cu μ Pillar with SnAg cap

Deposit property (relative)	INTERVIA™ 8540 Cu Pillar	XP Formulation A Cu Pillar
Surface profile	Domed (TIR >0)	Flat (TIR ~ 0)
Surface morphology	Smooth	Smooth
Organic incorporation in bulk Cu	Relatively low ($<20\text{ppm}$ total)	Relatively low ($<20\text{ppm}$ total)
Compatibility with SnAg capping	Compatible	Compatible

Table 1: Comparison data of Dow's commercial product and a new experimental Cu Pillar formulation.

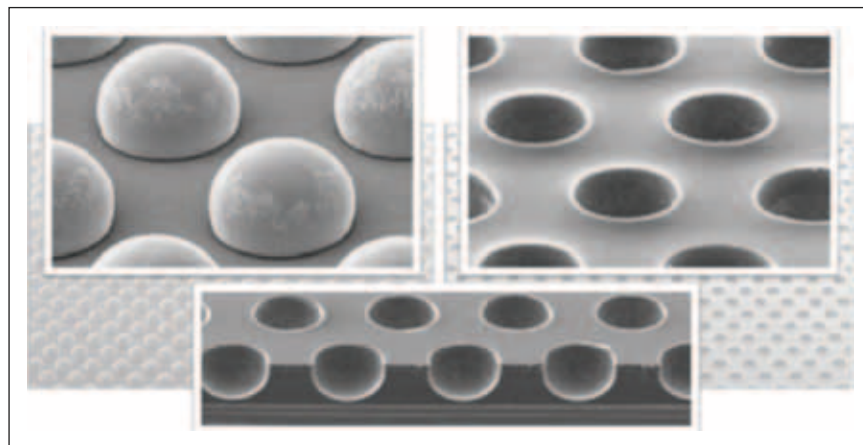


Figure 2: Even dense, C4-bumped wafers debond cleanly: SnAg solder bumps after debonding (left), BCB-based temporary bonding adhesive film after debonding (right, below)

deposits; void-free performance (X-ray); smooth surface morphology (as-plated and post-reflow) and a smooth, void-free interface with Cu Pillar.

Temporary Bond/Debond

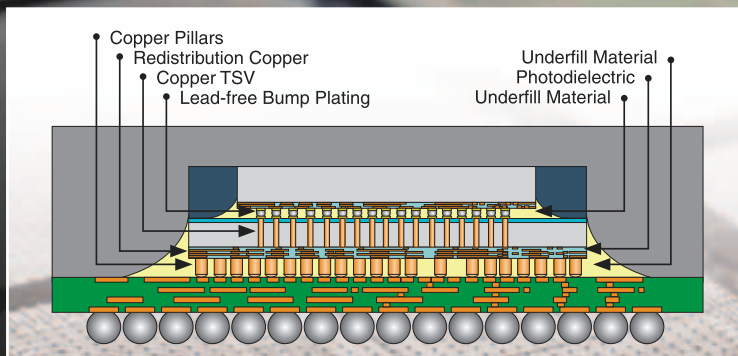
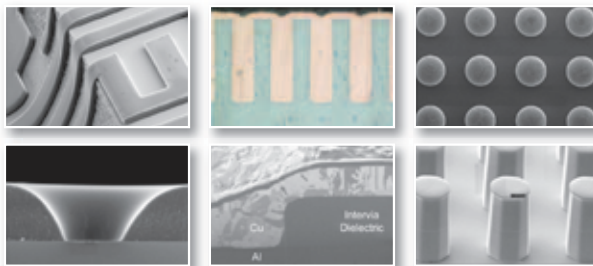
When it comes to temporary bonding, the gating technical issue has been with

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With **Innovation** Comes **Revolution**



Leading-edge packaging schemes are spurring a revolution in electronics. Dow Electronic Materials is there with a wide range of innovative metallization, dielectric, lithography and assembly materials – all delivered with global support from technical labs positioned close to customers. These are the innovations that drive the revolution.



Electronic Materials

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the debonding step. Dow's BCB dielectric material (CYCLOTENE™ 3000 Series Dielectric) is well-established as a useful permanent bonding adhesive due to high thermal stability, high chemical resistance, and low temperature curing. BCB has now been successfully modified to make it easily releasable from various surfaces, making it suitable for temporary bond/debond processes. An adhesion promoter is spin-coated onto the carrier wafer so that when it is debonded using mechanical lift-off at room temperature, the adhesive goes with the carrier and leaves the device wafer free of adhesive material (Figure 2) for a clean debond. Additionally, this material withstands high temperatures ($>300^{\circ}\text{C}/1\text{ hr}$) and bonds at low temperatures. Final cure is performed in a batch oven process with no alignment shift, for increased throughput and reduced cost-of-ownership (CoO).

Pre Applied Underfill

After backside processing, these thin devices must be assembled into stacked-die structures. Dow has developed a pre-applied underfill that allow for simultaneous electrical and adhesive die bonding. This material has performed well when applied as a wafer-level underfill for bonding Cu Pillars with $25\mu\text{m}$ diameter and $50\mu\text{m}$ pitch on thinned die, achieving good uniformity and thickness. It also addresses the fine pitches required for stacking logic SoCs with TSVs. (Figure 3).

Low Stress High Performance Dielectrics

Another issue resulting from thinner substrates is increased stress and wafer bow imparted by the current cured dielec-

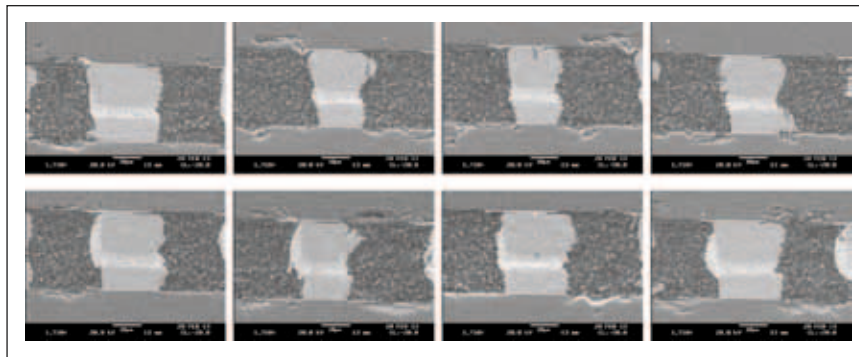


Figure 3: 100% electrical joining of 1600 solder joints per daisy chain.

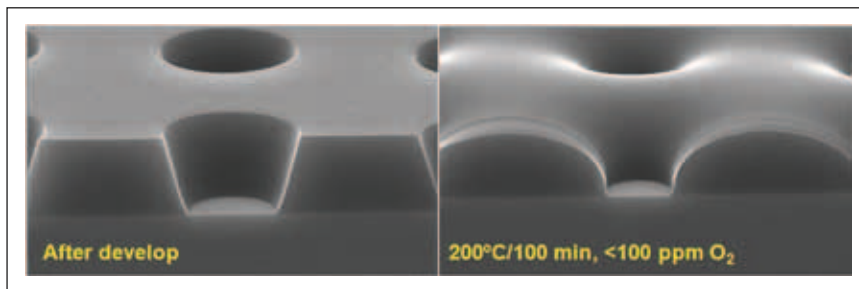


Figure 4: 70° tilt cross sections SEM of XP120201 depicting $5\mu\text{m}$, 1:2 contact holes after develop (left) and after soft cure (right).

tric materials. Dow has developed a photo-dielectric material that again builds on the thermal, electrical and chemical stability of BCB-based materials.

The new polymer is compatible with conventional TMAH-based developers, vs. the traditional solvent-based BCB photo-dielectric. The new aqueous-developable BCB photodielectric material can easily produce patterned features to $5\mu\text{m}$ and below, with aspect ratios of 2:1. It exhibits low-temperature cure, high thermal stability with low outgassing, and excellent mechanical properties.

Conclusion

For Dow, it makes sense to tap into robust, well-established materials technologies and adapt them to suit the requirements of next-generation technologies, rather than starting from scratch. In this way, proven chemistries can be extended to suit new applications while leveraging the benefits for existing requirements. As a result, a full suite of compatible chemistries are now ready to meet the needs of next-generation WLP, 2.5D and 3D packaging technologies.

For more information, go to www.dow-electronicmaterials.com. ♦

Henkel News



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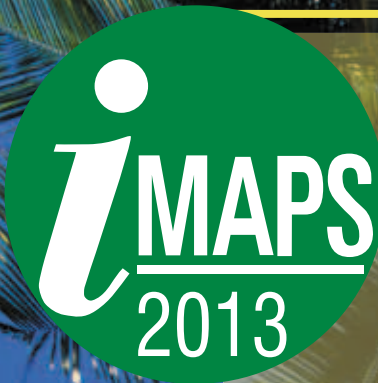
change its performance. For example, a manufacturer may design a pressure sensor that has a certain sensitivity. If the material properties change over time and experience shrinkage, for instance, the calibration changes and the pressure output may be far from satisfactory. If the package planarity is slightly off, performance of

the MEMS device may suffer. For critical applications such as air bag deployment or braking systems, inferior calibration could be catastrophic. Ensuring high performance materials that are in balance is essential and where Henkel's tested and market-ready materials deliver an advantage.

For trusted, proven MEMS materials, a full solutions approach, quick materi-

als delivery for fast production ramp-up, supply chain simplification, global support and capability, along with an expert, knowledgeable team, Henkel is the obvious – and only – choice.

To find out more about Henkel's comprehensive MEMS materials, go to www.henkel.com/electronics or call +1-888-943-6535 in the Americas, +32 1457 5611 in Europe or +86 21 3898 4800 in Asia. ♦



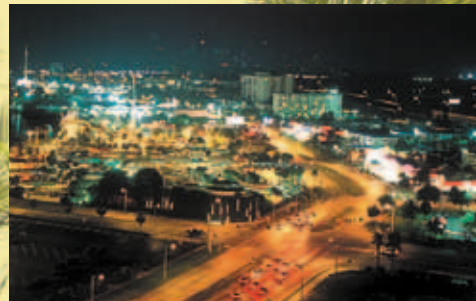
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Medical MEMS – Understanding the Healthcare Industry

Sam Bierstock, MD, BSEE

Physician (Internal Medicine and Ophthalmic Surgery), Electrical Engineer, Medical Informaticist
Founder, Champions in Healthcare

AS HEALTHCARE HAS BEEN THRUST into the digital world, and as the Medical MEMS Technology industry's interest in healthcare grows exponentially, many issues pertaining to the accumulation of healthcare data have come to light. These include privacy and confidentiality, sharing of data, use of accumulated data for epidemiological purposes, development of quality of care issues, protocols and guidelines, etc.

While the ability of MEMS devices to deliver data is of great value to analysis and quality of care determinations, it is important to define the additional value offered for clinical decision making. Anyone entering the Medical MEMS Technology arena must have a clear understating of the best use of the data to be generated and to whom it will be most useful.

Generating reports is one thing. Receiving, analyzing, selecting key elements and basing decisions on a constant stream of data is something else. Clinicians are busy, pressured and constantly multitasking. While non-clinicians may gain some insight into physician workflow, unless you have been in the trenches of clinical care delivery, it is not possible to understand physician "Thoughtflow™". I first defined clinical Thoughtflow™ a decade ago as the process by which physicians and other clinicians access, assess, prioritize and act upon data. Thoughtflow™ differs by specialty and indeed, by individual. A cardiac surgeon has little analysis to do when receiving an alert from an intelligent coronary artery stent indicating a drop in flow through the device. On the other hand, an internist may have to take a fair amount of time to review a report with a cascading stream of blood glucose levels over a lengthy period of time, and relate the results to eating and medication patterns for a diabetic patient. The risk

of overwhelming the clinician in such an instance is substantial.

While the MEMS technology industry has clearly found the Healthcare Industry, the reverse is not true. The mainstream medical informatics world is just beginning to grasp what is out there — and when a full comprehension of MEMS capabilities is achieved, the demand for medical MEMS devices will be staggering. The medical and research communities are highly creative, and the request for function-specific medical MEMS devices is likely to soon outpace the industry's ability to produce them. The FDA is likely to make the process of meeting demand even slower — especially for implantable wireless devices. As a medical informaticist with more than 30 years in the informatics world, I am still stunned by how few of my colleagues even know what MEMS devices are.

But I have seen this movie.

I tried to convince people about the potential for Internet-based medical records and the need for security of private healthcare information in the mid-1990's, but it took another 10 years for information to begin to move on to the Internet and into the cloud. I tried to convince a major (and then very young) cell phone manufacturer of the enormous potential for hand-held devices in healthcare in 1998. I was thanked and wished a good day. Healthcare is a sluggish industry, steeped in stagnation and inertia, and deeply immobilized by the endless crises of the moment. It has a difficult time differentiating fads from trends. Millions are spent and made on fads. Positioning for trends rarely extends to what is coming next — let alone what is coming after what is coming next. Governmental regulation and reimbursement challenges make maneuvering for survival a necessary primary priority.

It is also an industry that wallows in what it has to deal with at any given moment. Spending money on what may be coming is rarely on the radar.

Knowing how to position a medical MEMS device so as to highlight the value of its data-generating capability and its clinical pertinence is of paramount importance to success. This requires an intimate understanding of the issues that keep C-level decision makers awake at night, of healthcare practices, of clinical decision-making, of current policy-shaping legislative mandates, and of the fiscal pressures to which providers are subjected at every level. The healthcare industry is like no other industry, and the side of the road to gaining a foothold is littered with the failed remnants of businesses of all sizes — from start-up companies to multi-billion dollar corporate entities — who thought that their conventional "business smarts" would assure success. ♦

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SAM BIERSTOCK, MD, BSEE is a Physician (Internal Medicine and Ophthalmic Surgery), Electrical Engineer, and Medical Informaticist. Dr. Bierstock is a nationally recognized authority on healthcare and healthcare information technology, author of 4 books, more than 100 published professional articles, and international lecturer. He is the Recipient of the George Washington Honor Medal, Freedoms Foundation for his work on behalf of our nation's veterans.

For more information on Dr. Bierstock visit www.sambierstock.com.

Copper Pillar μ Bumps

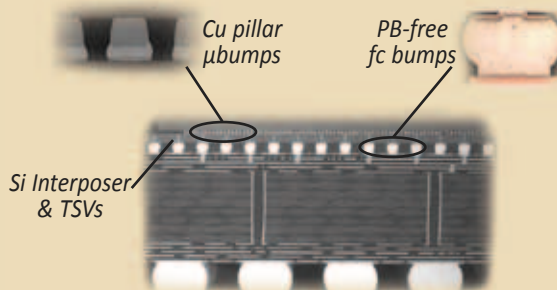
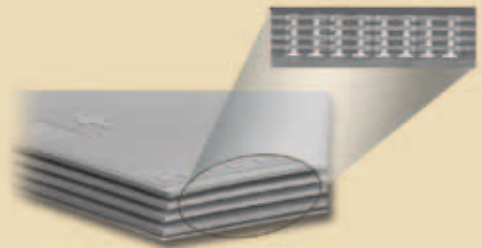
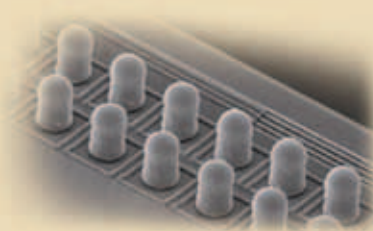
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- Controlled stress for ULK
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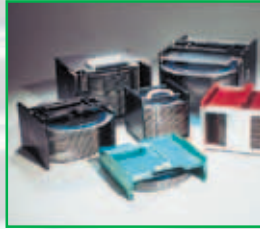
Copper Pillar μ Bumps



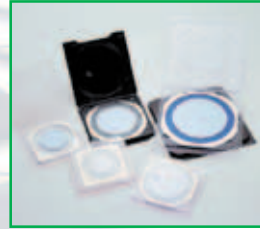
Magazines and Carriers for Process Handling Solutions



Film Frames



Film Frame
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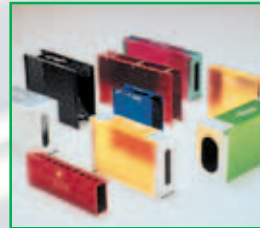
Grip Rings



Grip Ring Magazines



Grip Ring Shippers



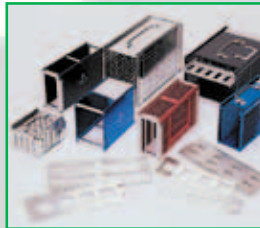
Lead Frame
Magazines - F.O.L./E.O.L.



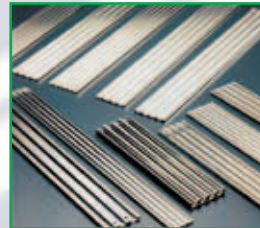
Stack Magazines -
E.O.L.



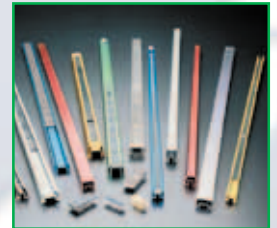
Process Carriers
(Boats)



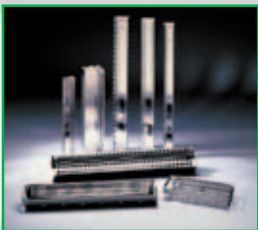
Boat Magazines



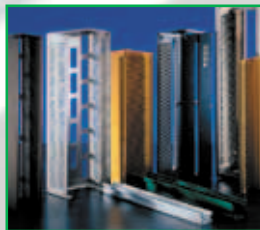
I. C. Trays -
Multi-Channel



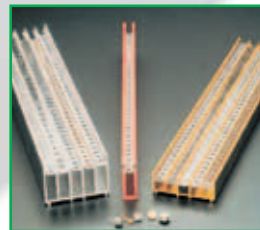
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